

Extended images in action

-efficient WEMVA via randomized probing

Rajiv Kumar, Tristan van Leeuwen and Felix J. Herrmann



SLIM



University of British Columbia

Motivation

- Subsurface image gathers are beneficial
 - AVA
 - WEMVA
- Need full-subsurface offset volumes
 - estimate *geological dips*
 - *velocity analysis* in complex geological structures

Motivation

- computation of *full*-subsurface offset volumes is computationally *prohibitively* expensive (storage & computation time)
- can't form full offset volumes but *action* on (random) vectors allows us to get information from *all* or *subsets* of *subsurface points*

Extended images

- Given two-way wave equations, source and receiver wavefields are defined as

$$\begin{aligned} H(\mathbf{m})U &= P_s^T Q \\ H(\mathbf{m})^* V &= P_r^T D \end{aligned}$$

where

$H(\mathbf{m})$: discretization of the Helmholtz operator

Q : source

D : data matrix

P_s, P_r : samples the wavefield at the source and receiver positions

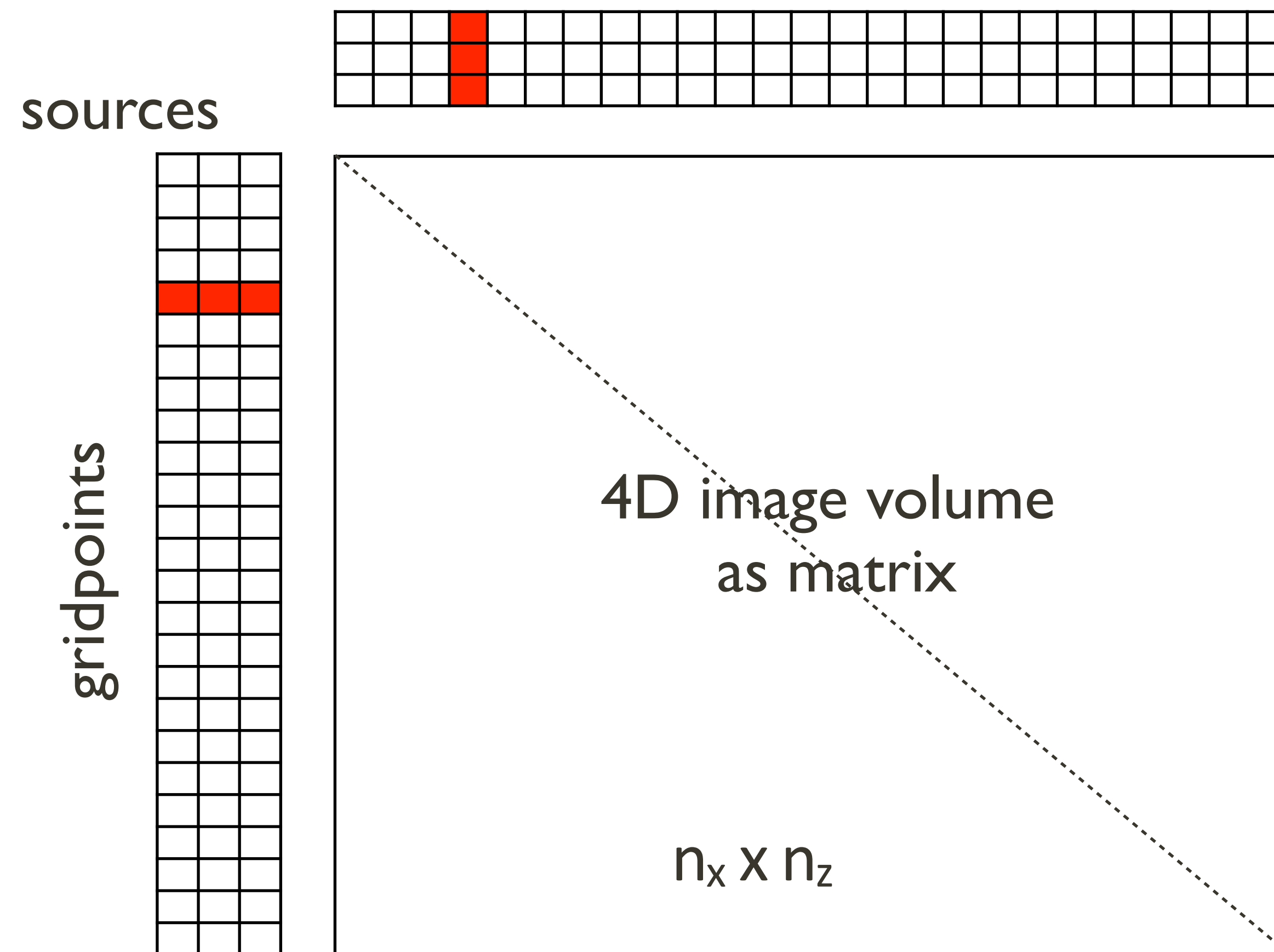
$\mathbf{m}$: slowness

Extended images

- Organize wavefields in monochromatic data *matrices* where each *column* represents a *common* shot gather
- Express *image* volume *tensor* for *single* frequency as a *matrix*

$$E = UV^*$$

Extended images



Extended images

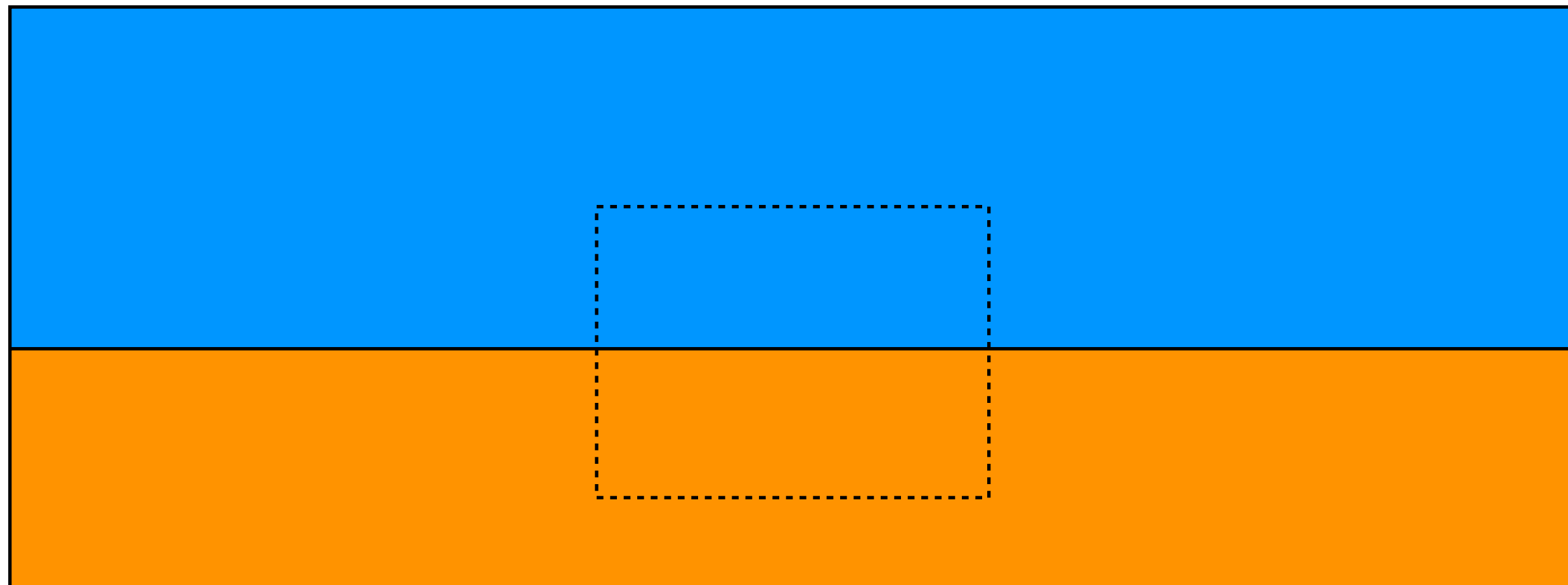
- Too expensive to compute (*storage and computational time*)
- Instead, *probe* volume with *tall* matrix $W = [\mathbf{w}_1, \dots, \mathbf{w}_l]$ **van Leeuwen 2012**

$$\tilde{E} = EW = H^{-1}P_s^T QD^* P_r H^{-1}W$$

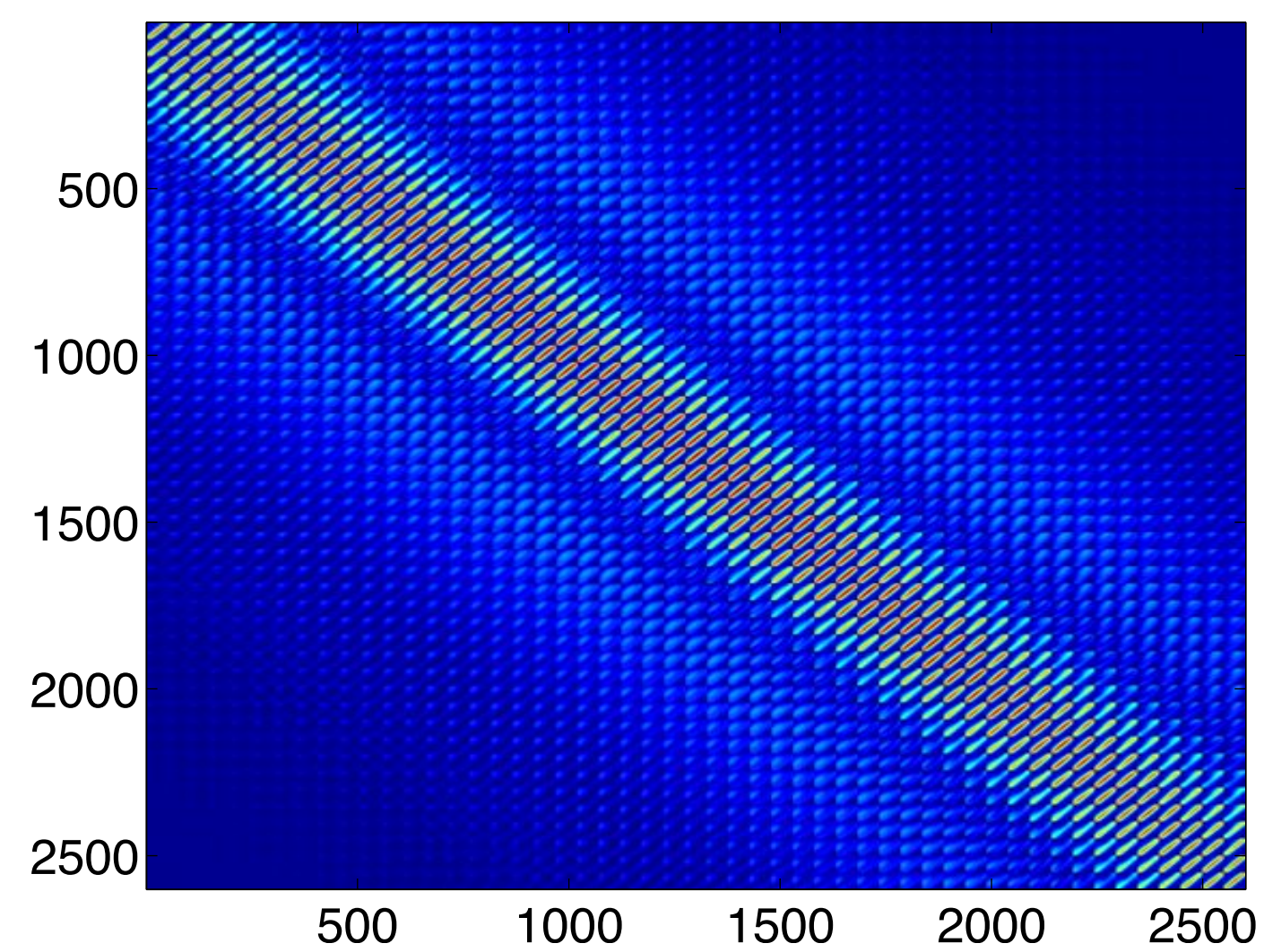
where $\mathbf{w}_i = [0, \dots, 0, 1, 0, \dots, 0]$ represents *single* scattering points

Extended images

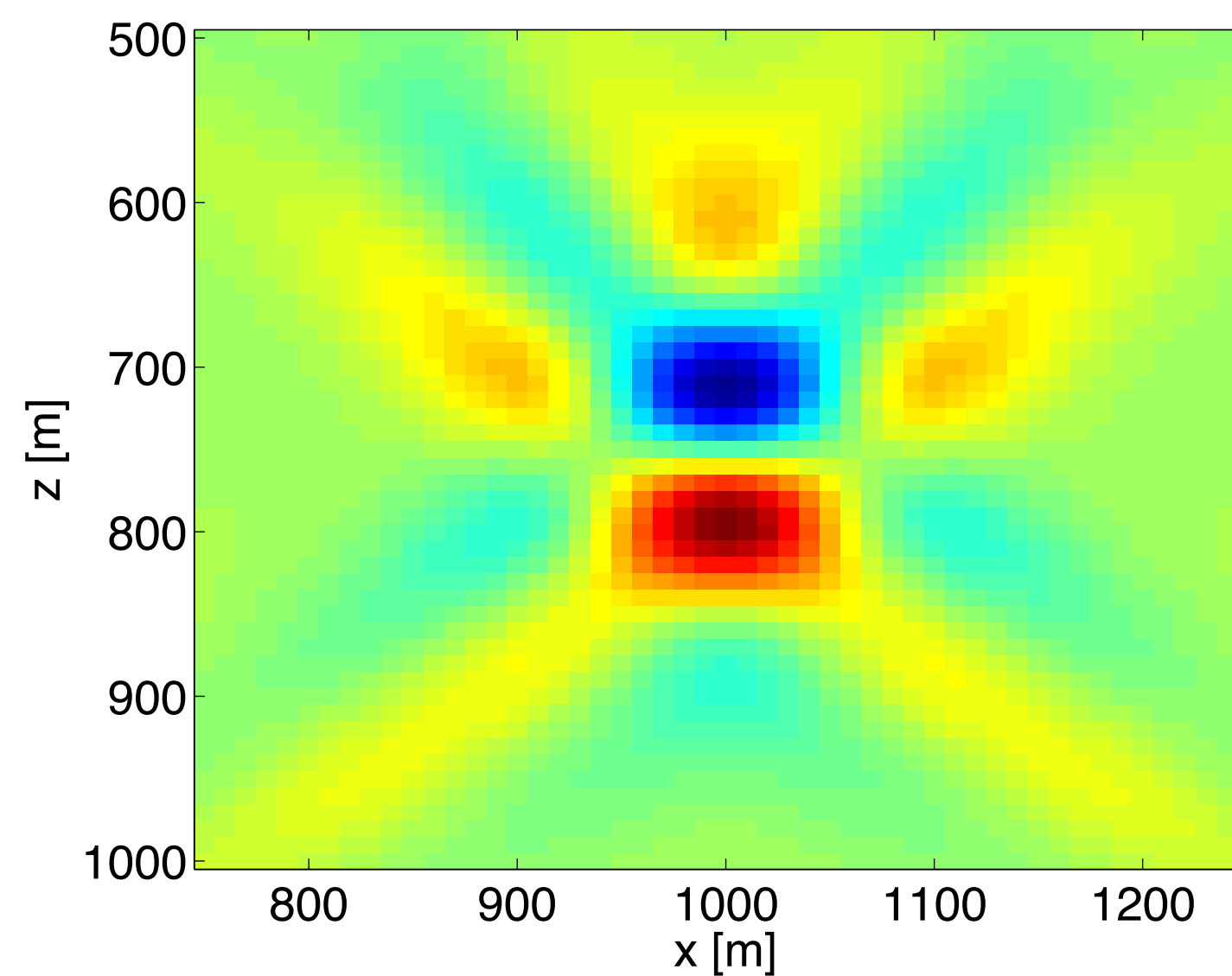
example for *one* layer



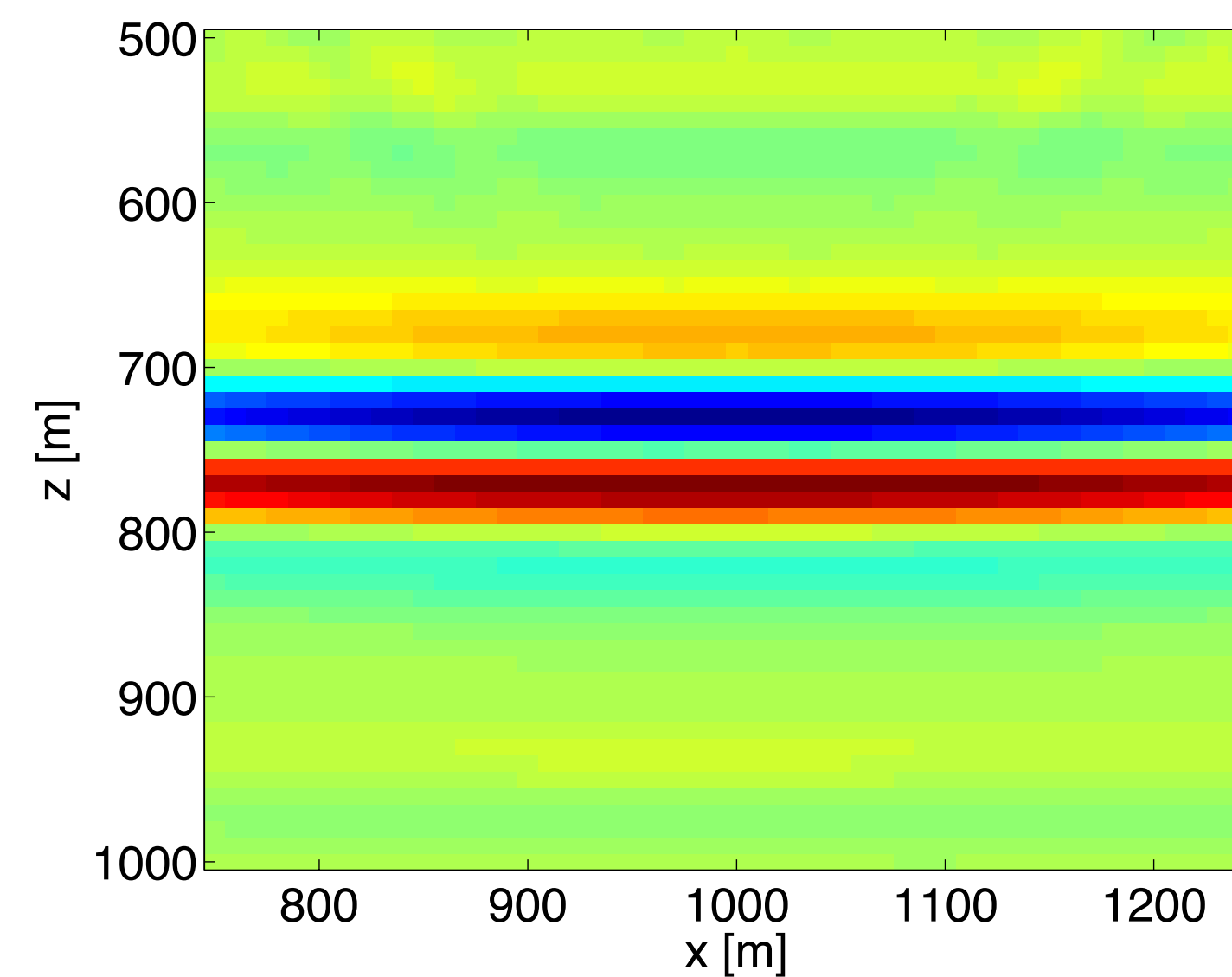
Extended images



full matrix



one column



diagonal

Computational costs

Full subsurface offset extended images:

	# of PDE solves	“flops for correlations”
conventional	$2N_s$	$N_s \times N_h$
mat-vecs	$2N_x$	$N_s \times N_r$

N_s - # of sources

N_r - # of receivers

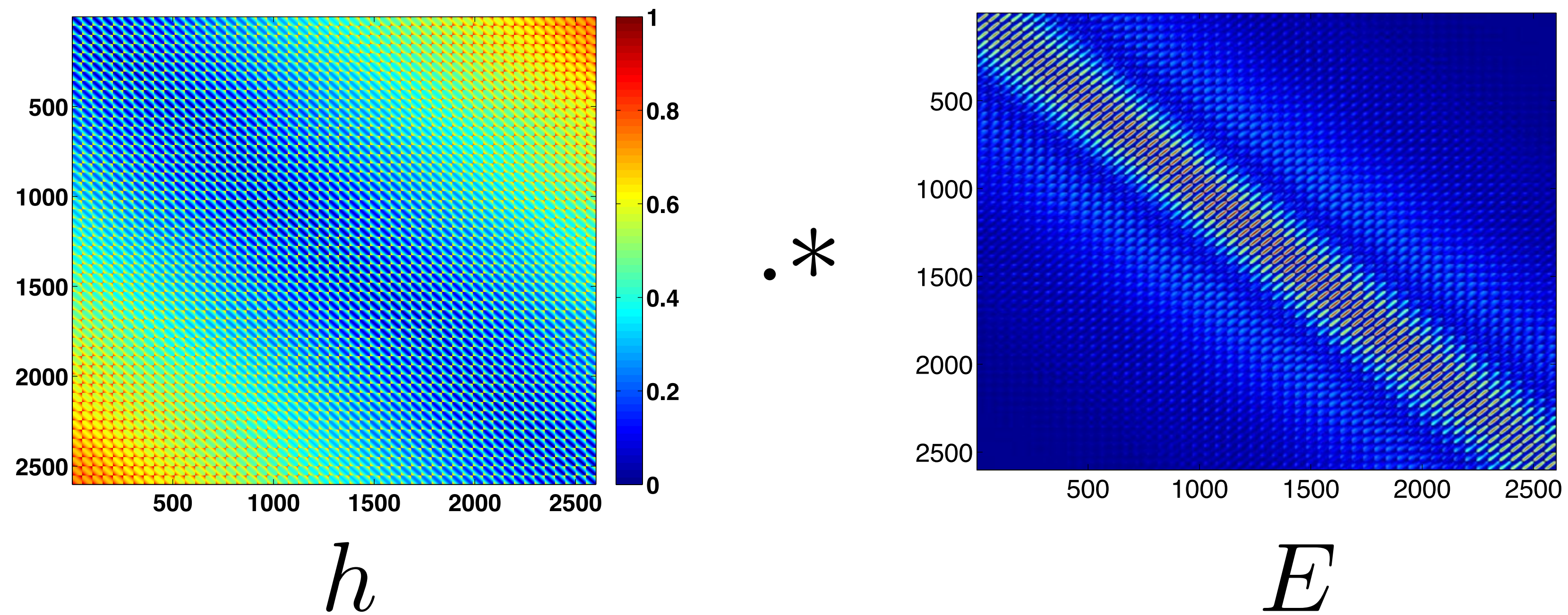
N_h - # of subsurface offsets

N_x - # of sample points

Biondo & Symes, '04 , Symes 2008, Sava & Vasconcelos, '11

WEMVA

[conventional method]

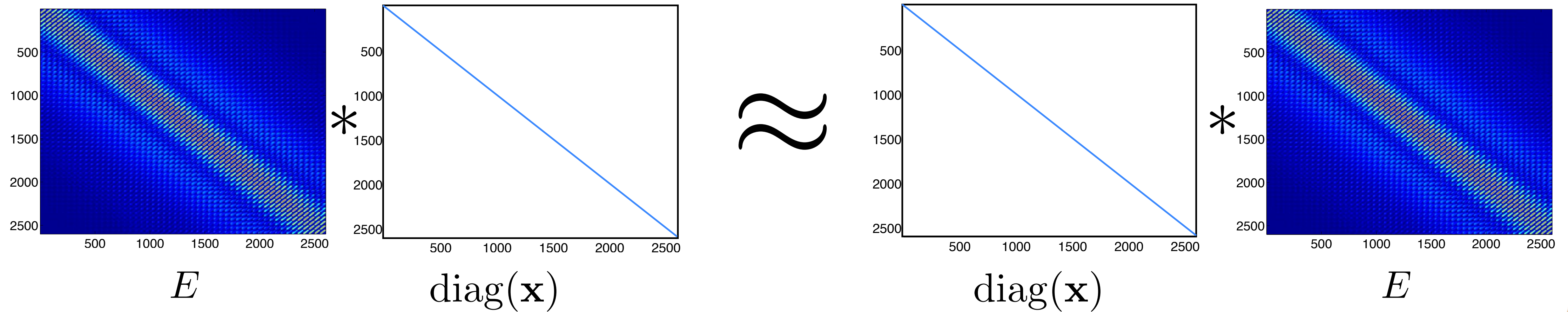


$\cdot *$ stand for element-wise multiplication

Focusing

[propose method]

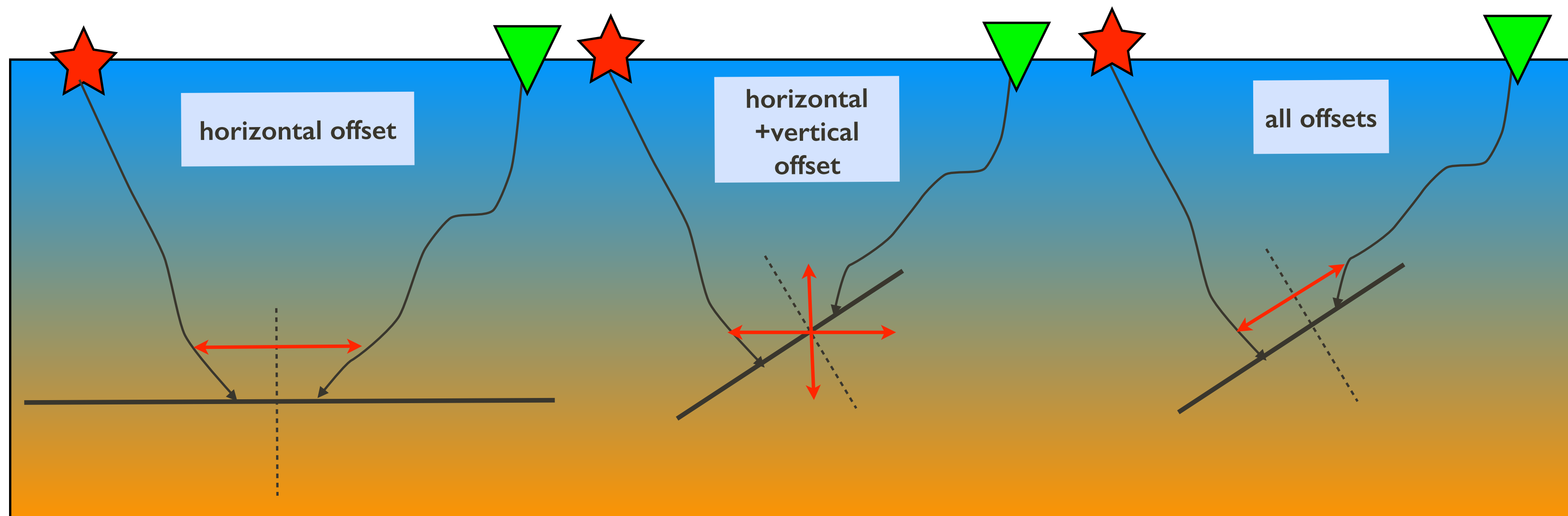
$$E \text{diag}(\mathbf{x}) \approx \text{diag}(\mathbf{x}) E$$



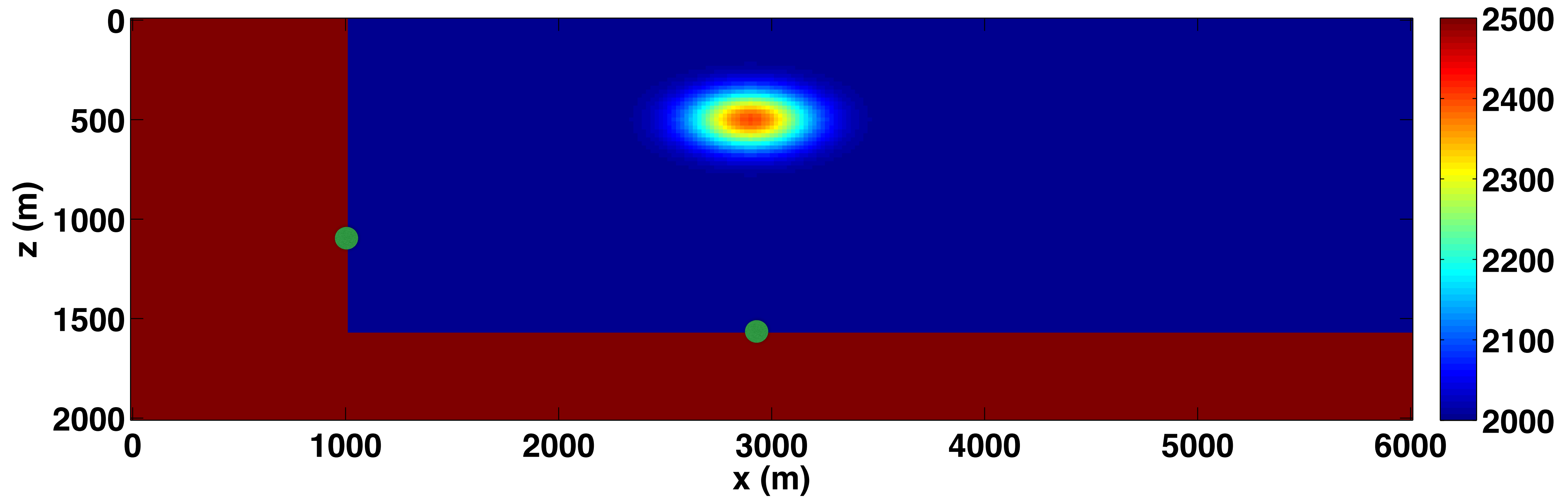
$*$ matrix-matrix multiplication

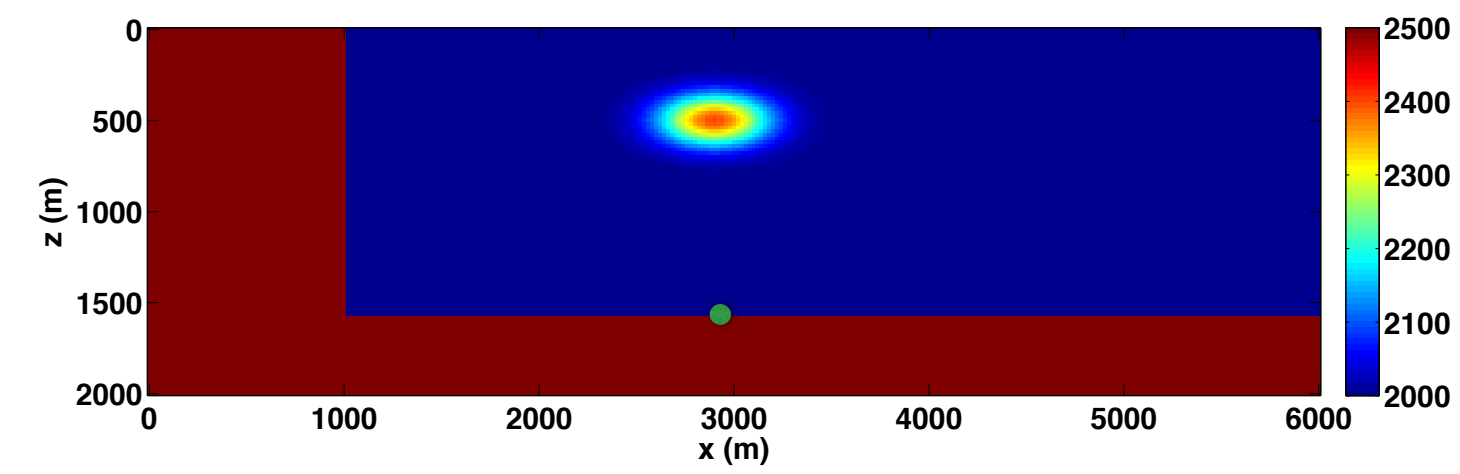
Focusing

where x represents horizontal, vertical or all offset.

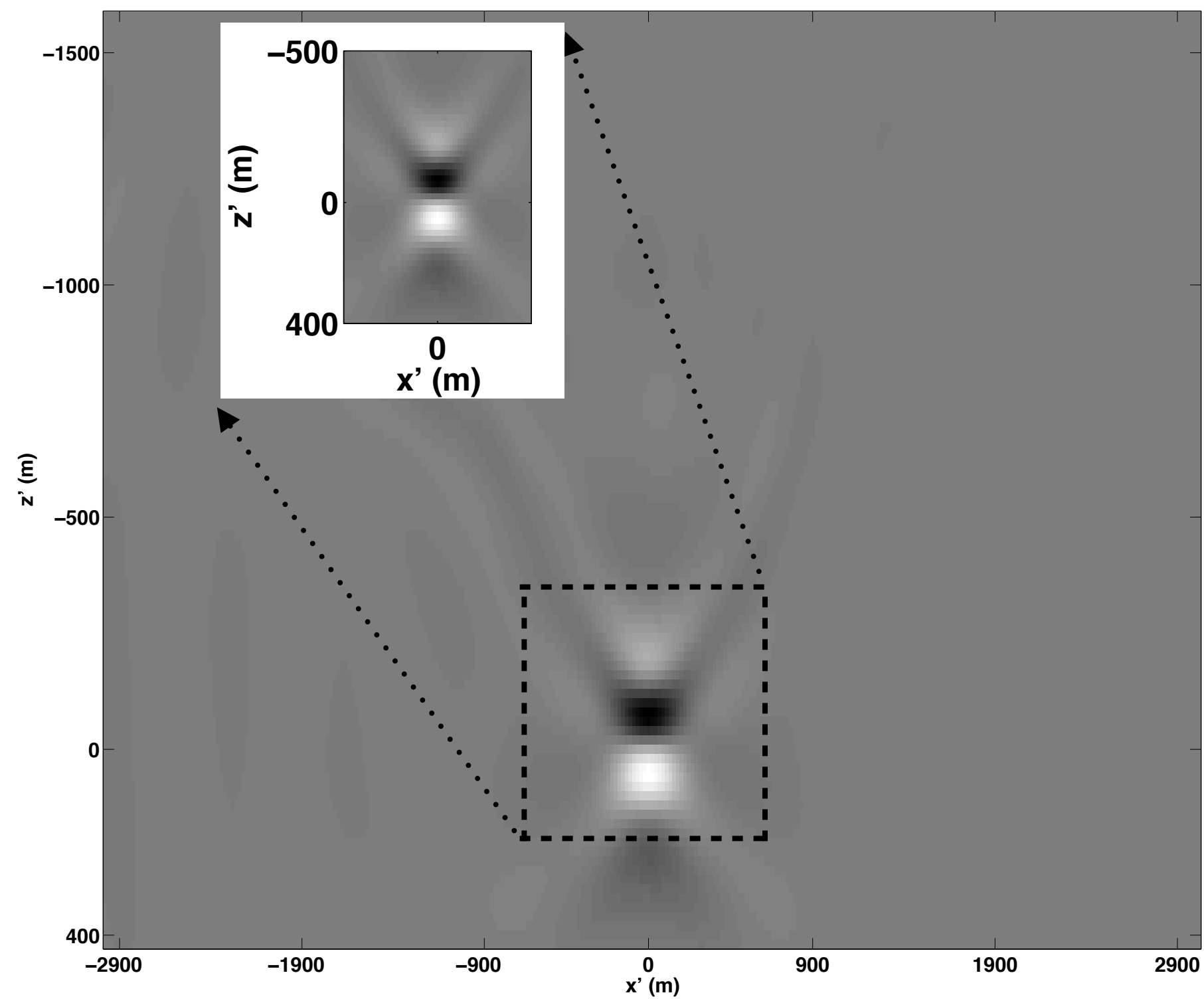


Why do we need all offsets

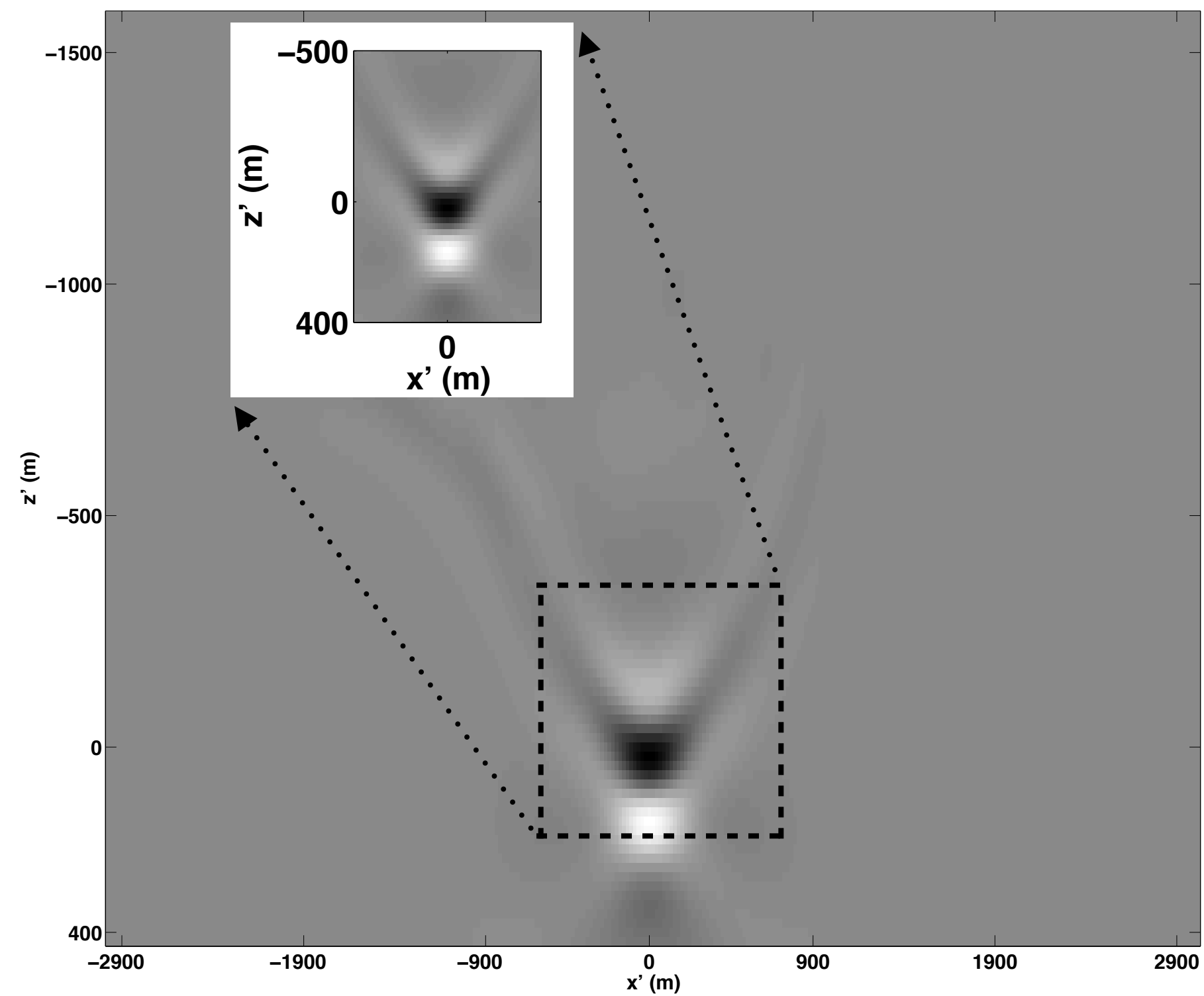




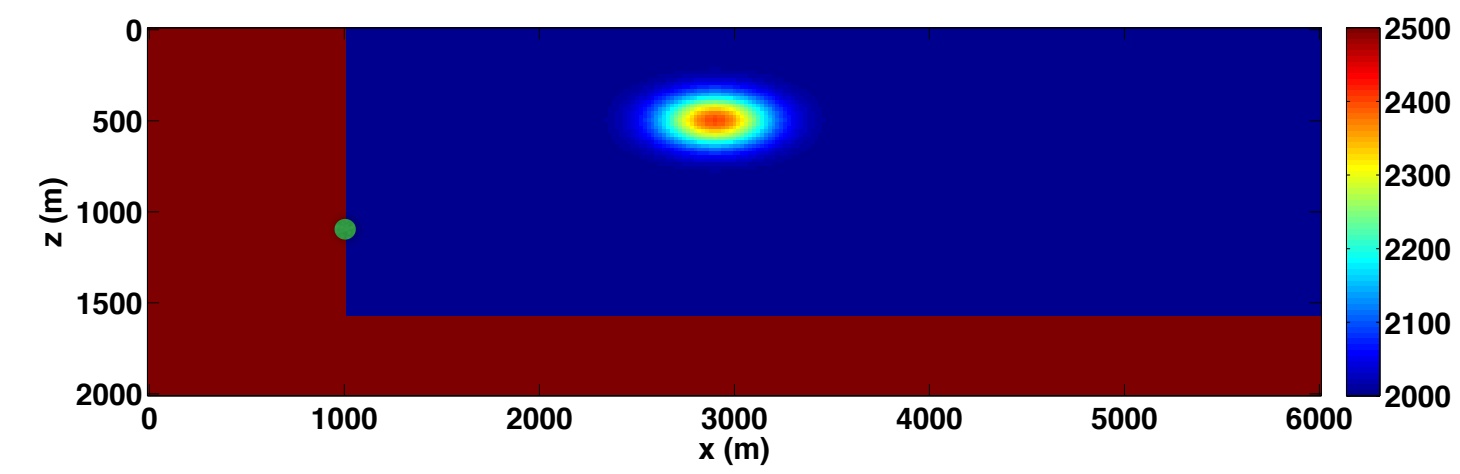
Why do we need all offsets



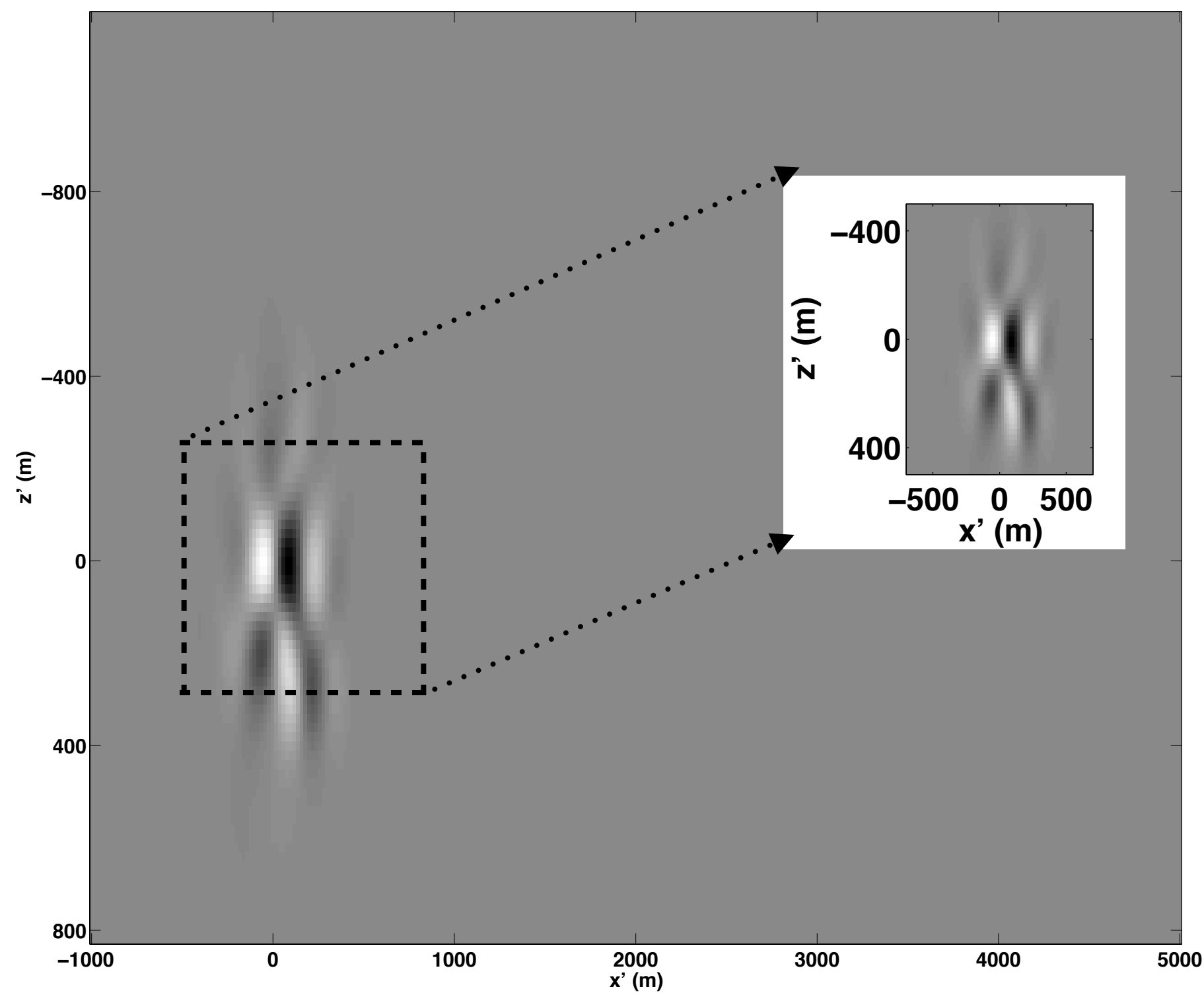
right velocity



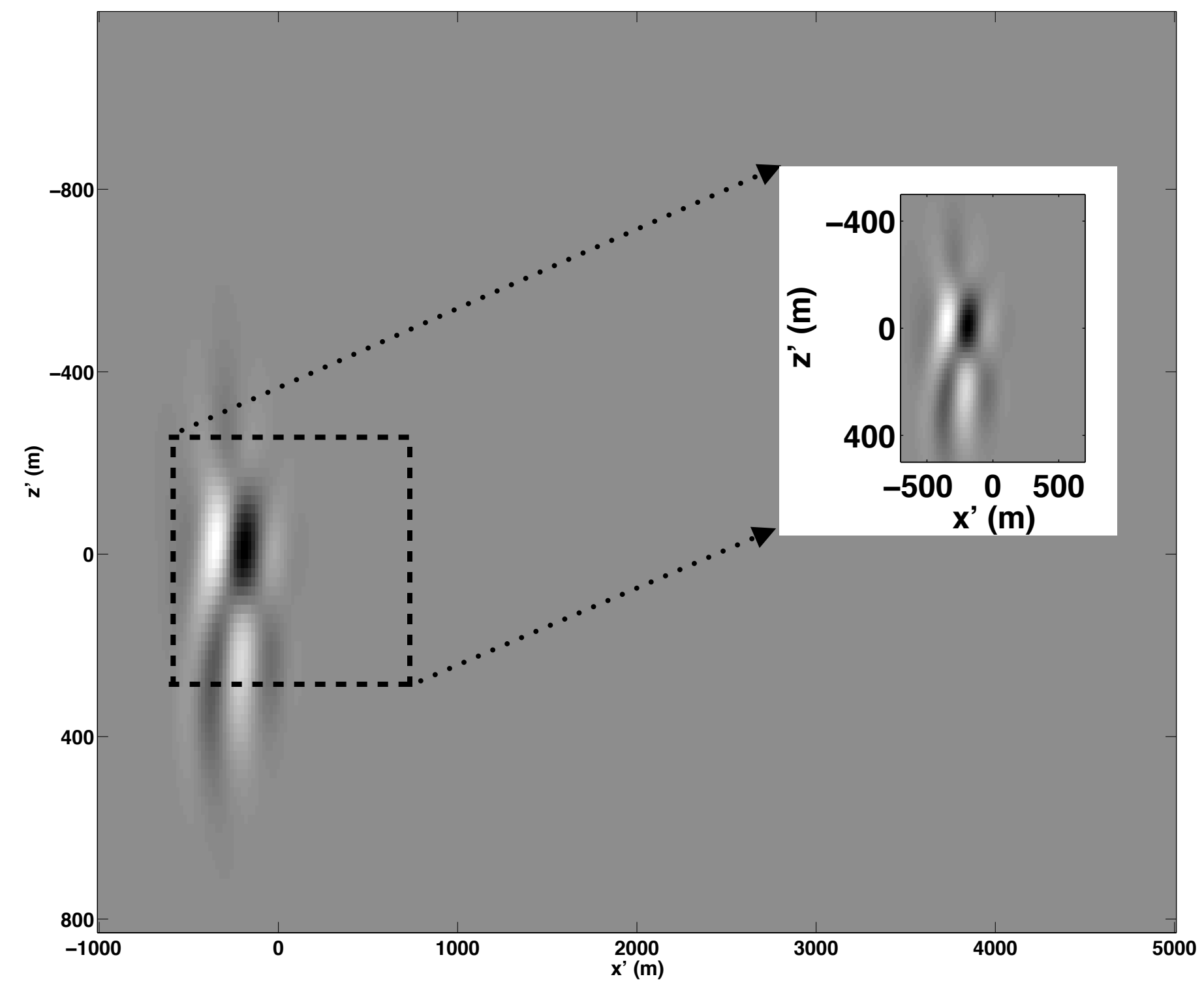
wrong velocity



Why do we need all offsets



right velocity



wrong velocity

Fast WEMVA w/ randomized probing

- Measure the error in some norm

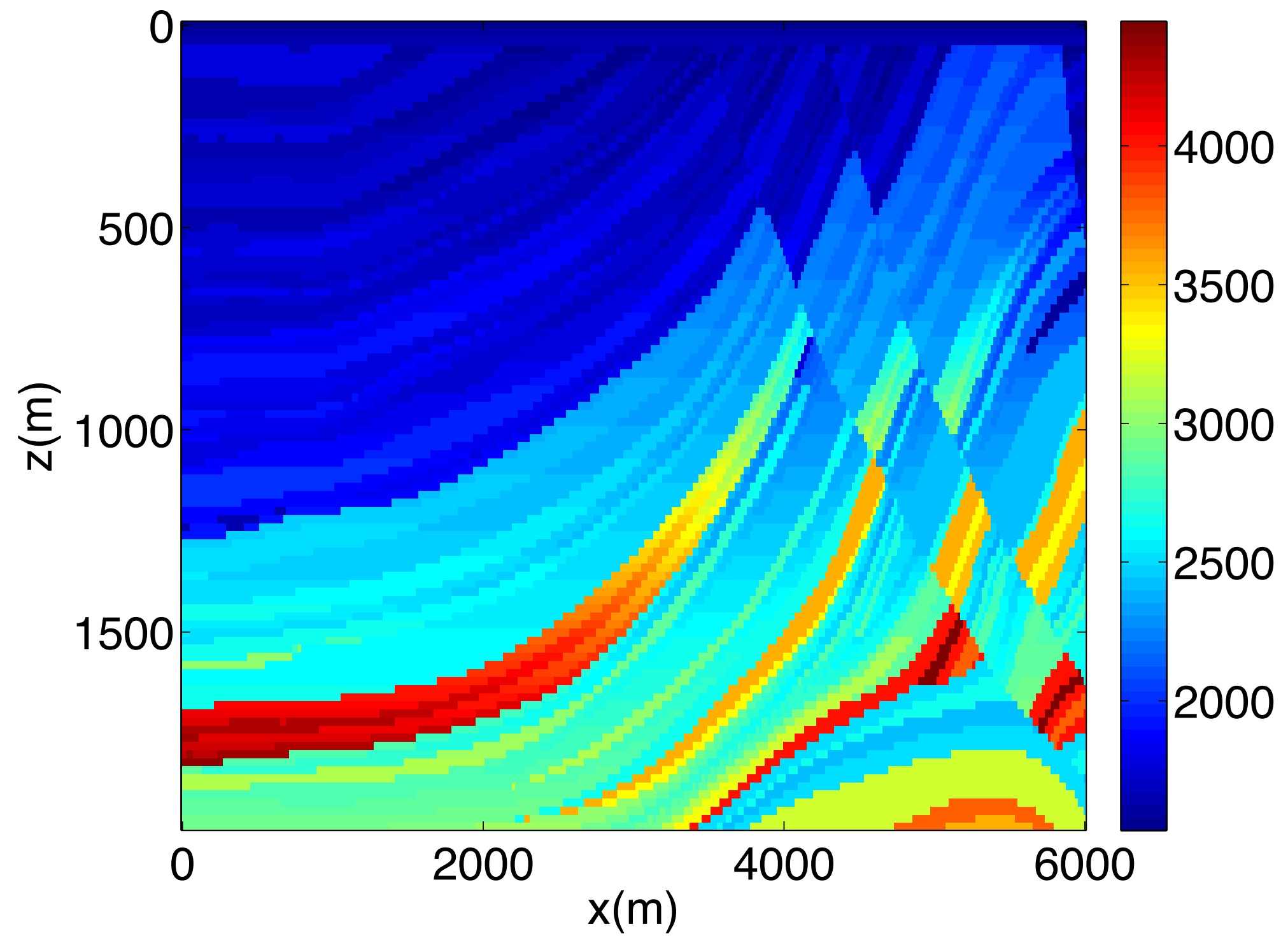
$$\min_{\mathbf{m}} ||E(\mathbf{m})\text{diag}(\mathbf{x}) - \text{diag}(\mathbf{x})E(\mathbf{m})||_?^2$$

- The *Frobenius* norm can be estimated via randomized trace estimation : [Avron and Toledo, 2011](#)

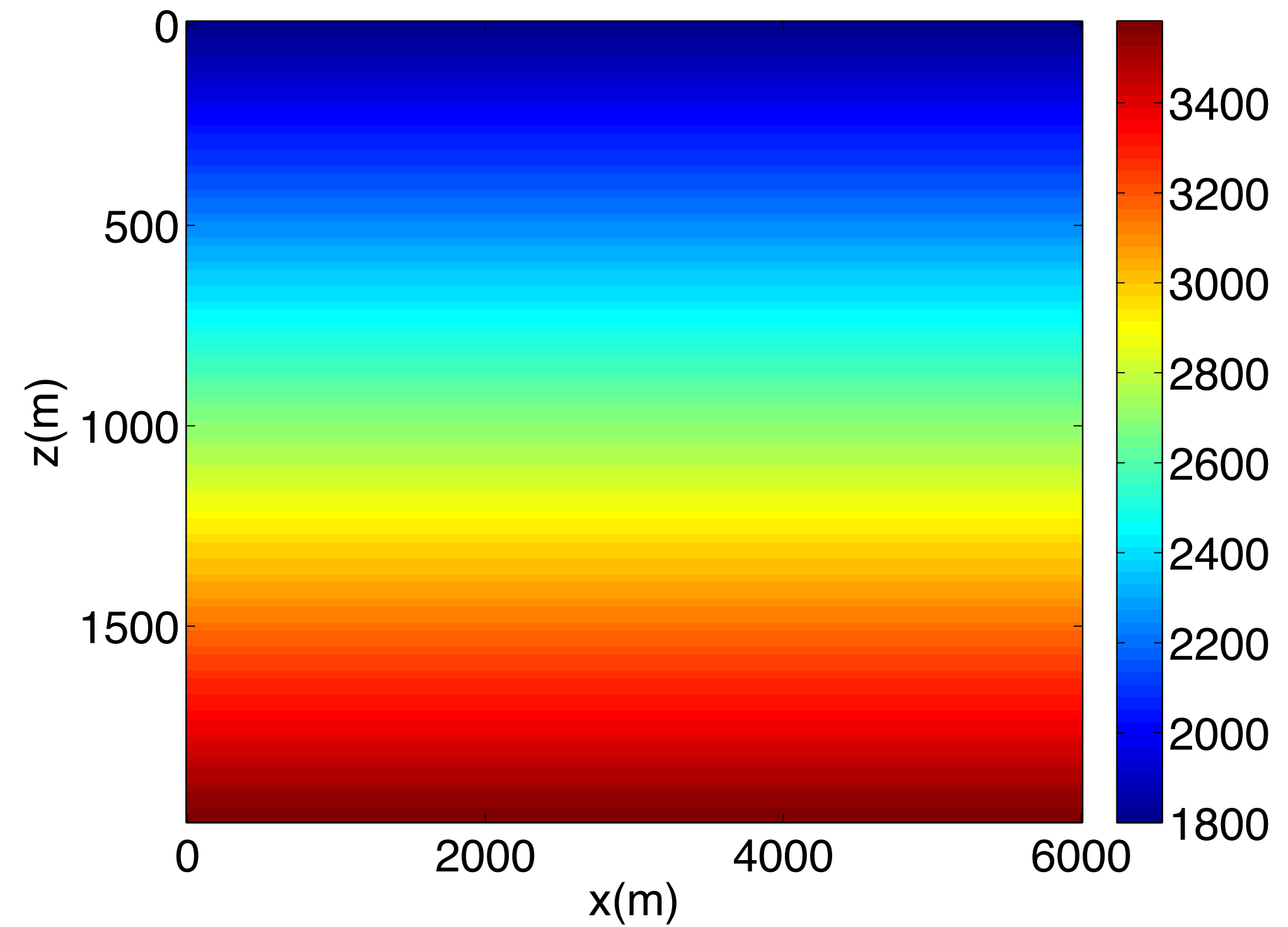
$$\begin{aligned} ||A||_F^2 &= \text{trace}(A^T A) \\ &\approx \sum_{i=1}^K \mathbf{w}_i^T A^T A \mathbf{w}_i = \sum_{i=1}^K ||A \mathbf{w}_i||_2^2 \end{aligned}$$

where $\sum_{i=1}^K \mathbf{w}_i \mathbf{w}_i^T \approx I$

Randomized probing [reflection]

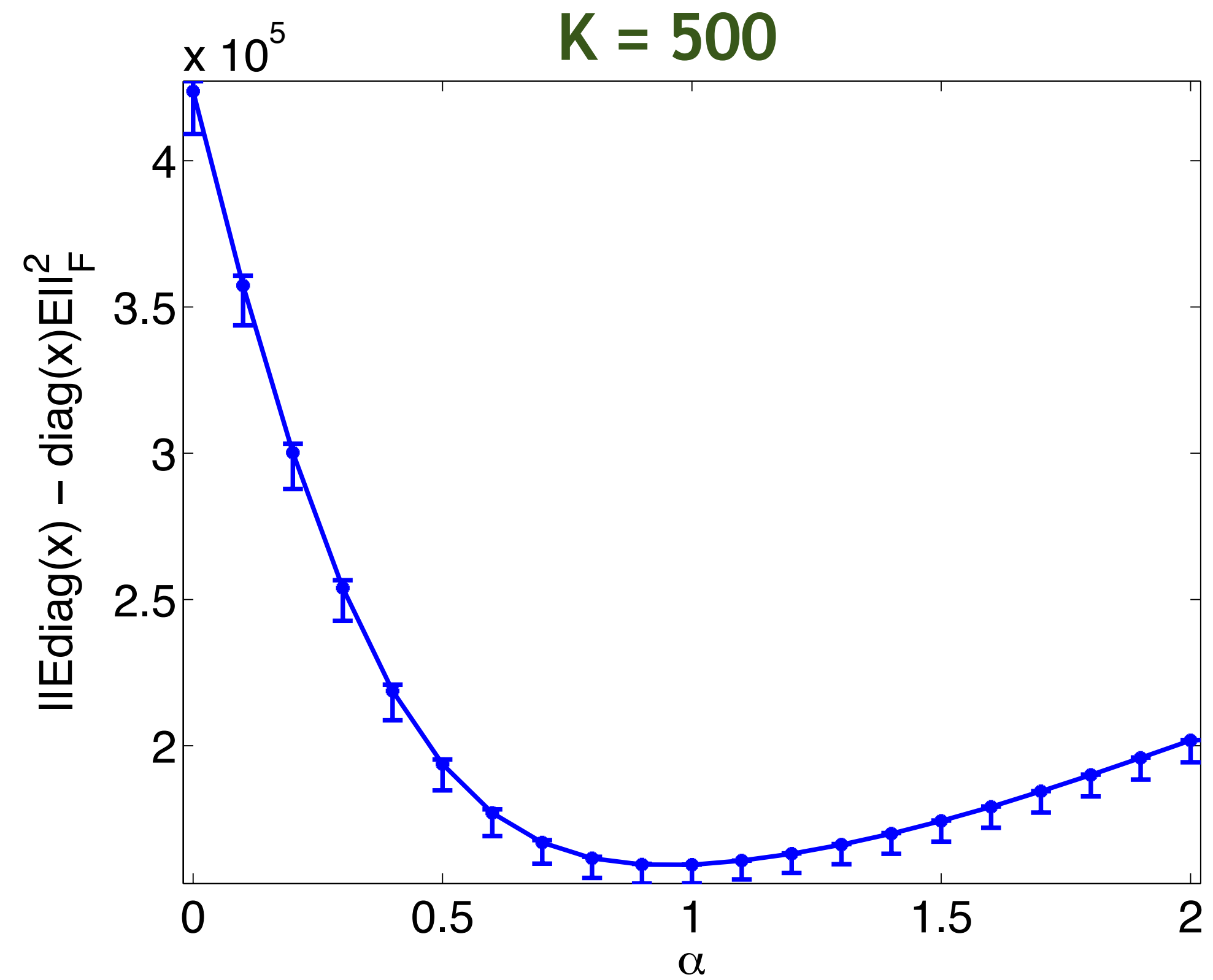
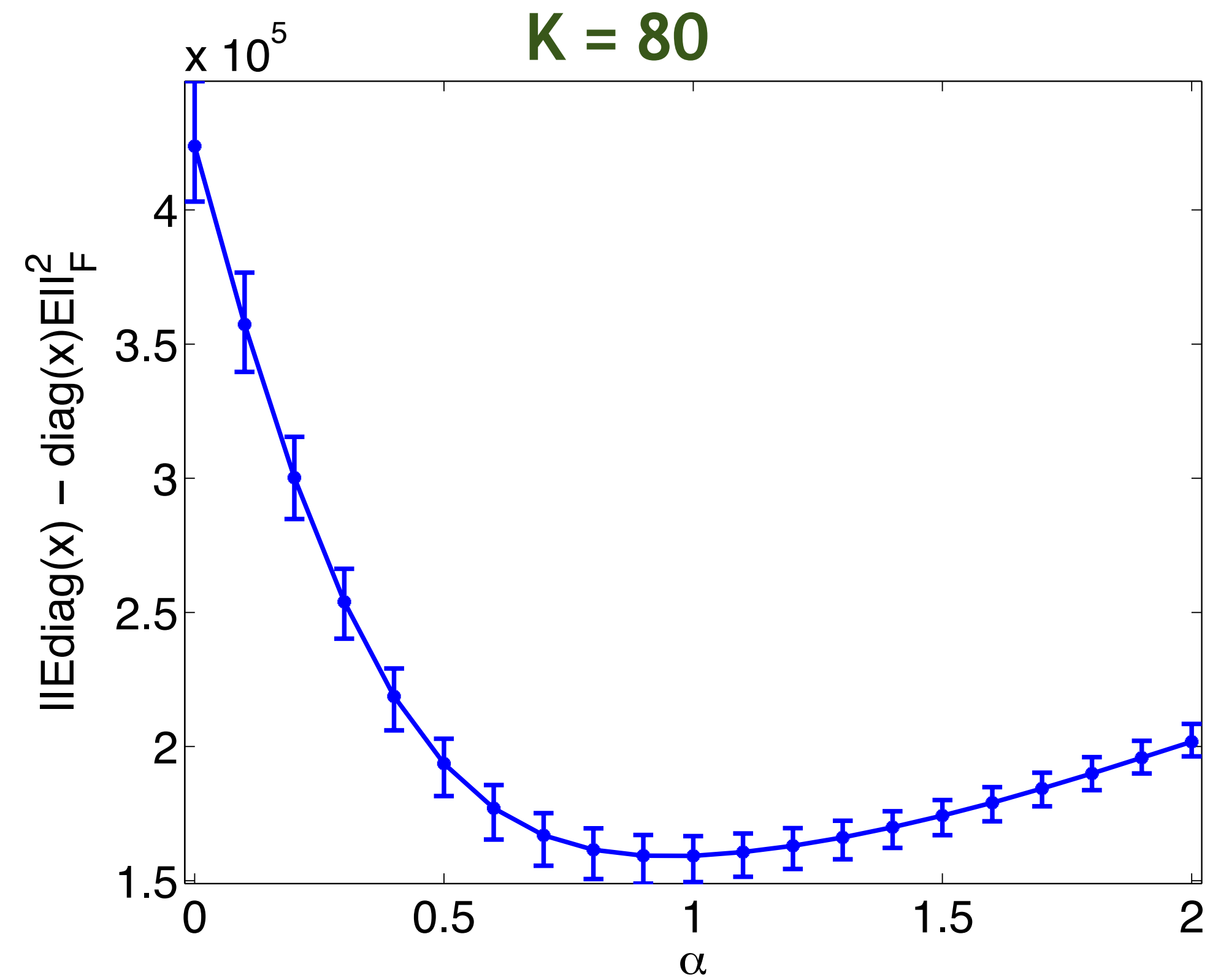


true model



initial model

Randomized probing [reflection]

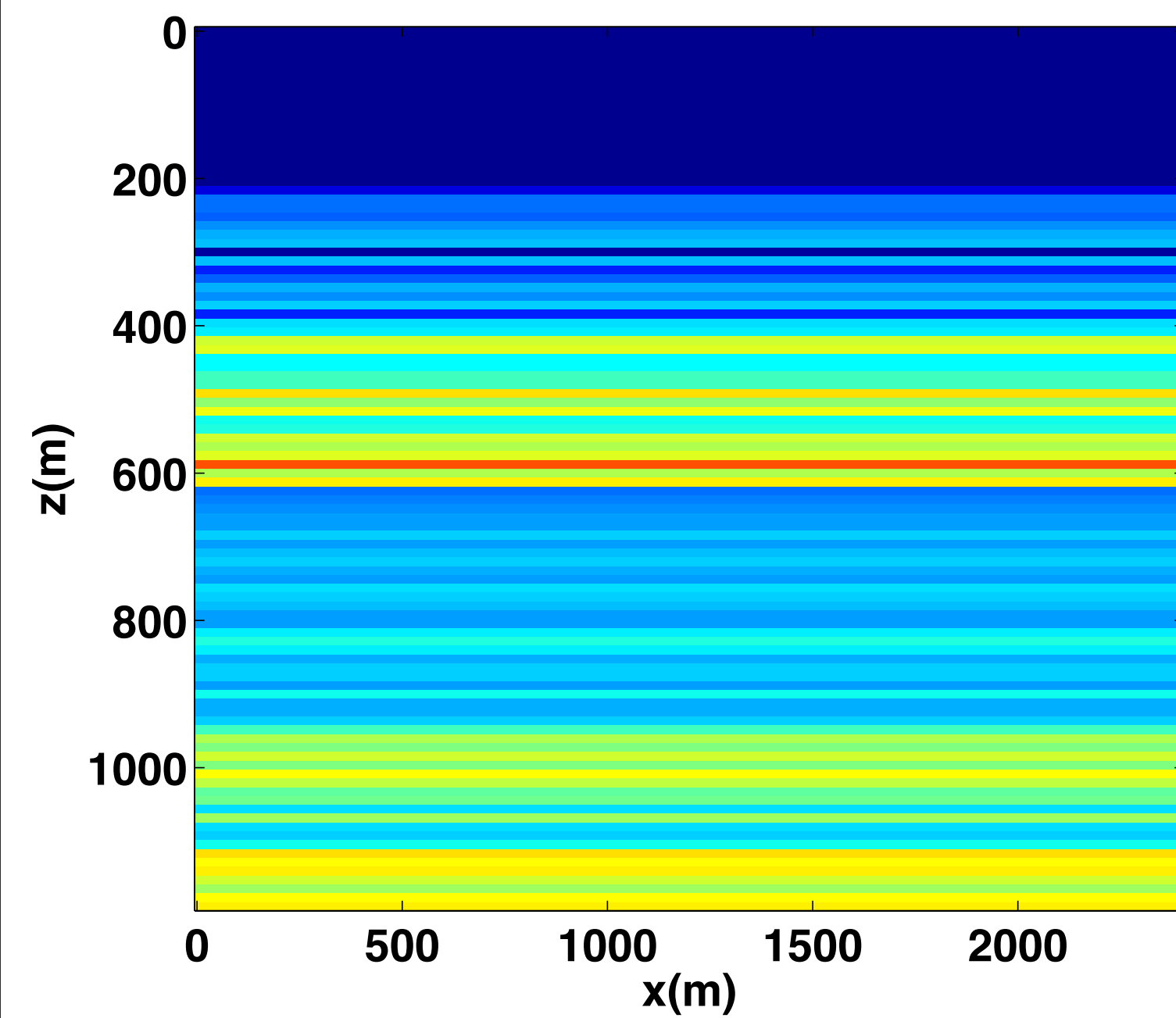


Applications

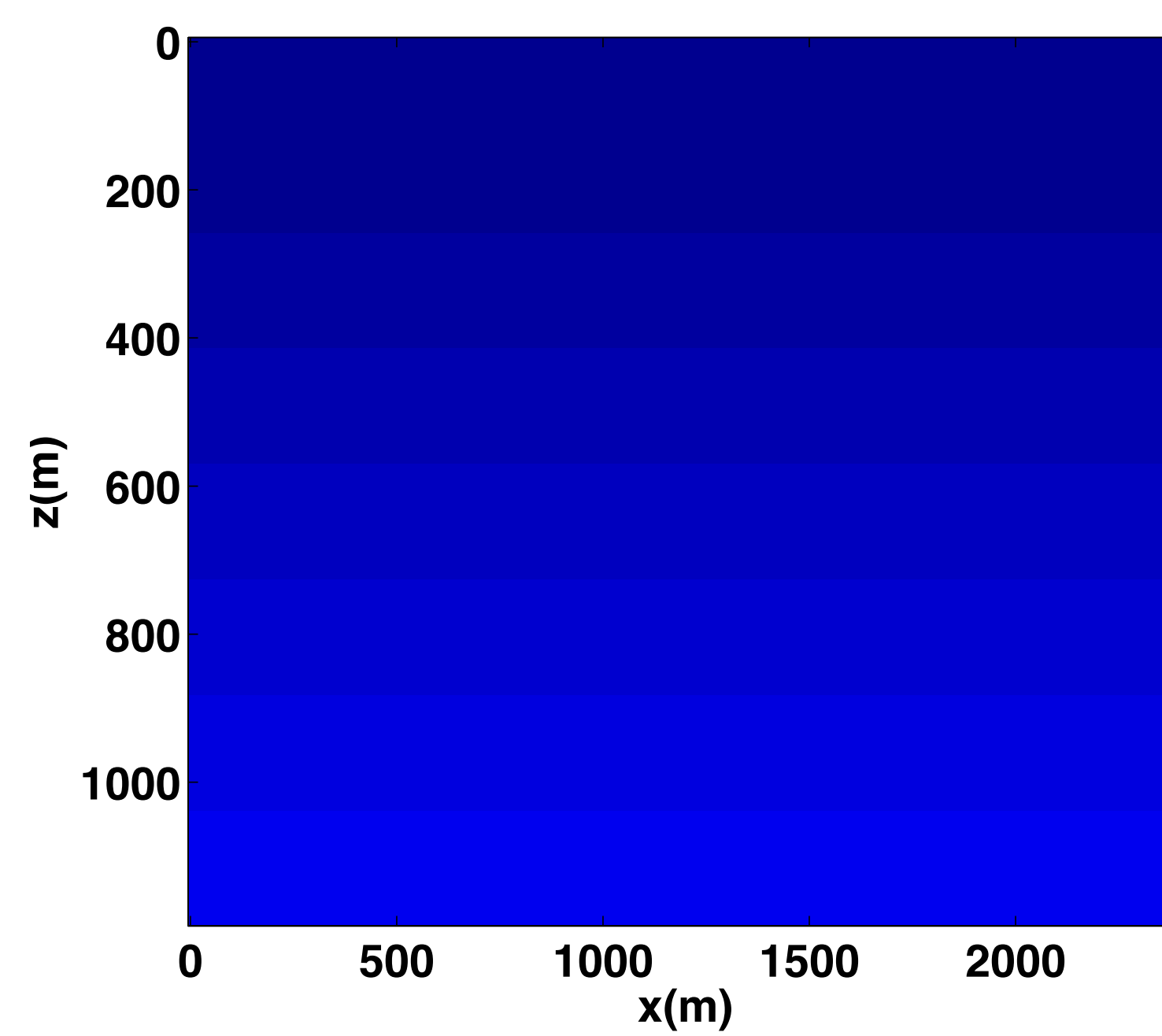
- Reflection wave
 - Reflector model
 - Lens model
- Diving wave
 - Vertical gradient

Reflector model

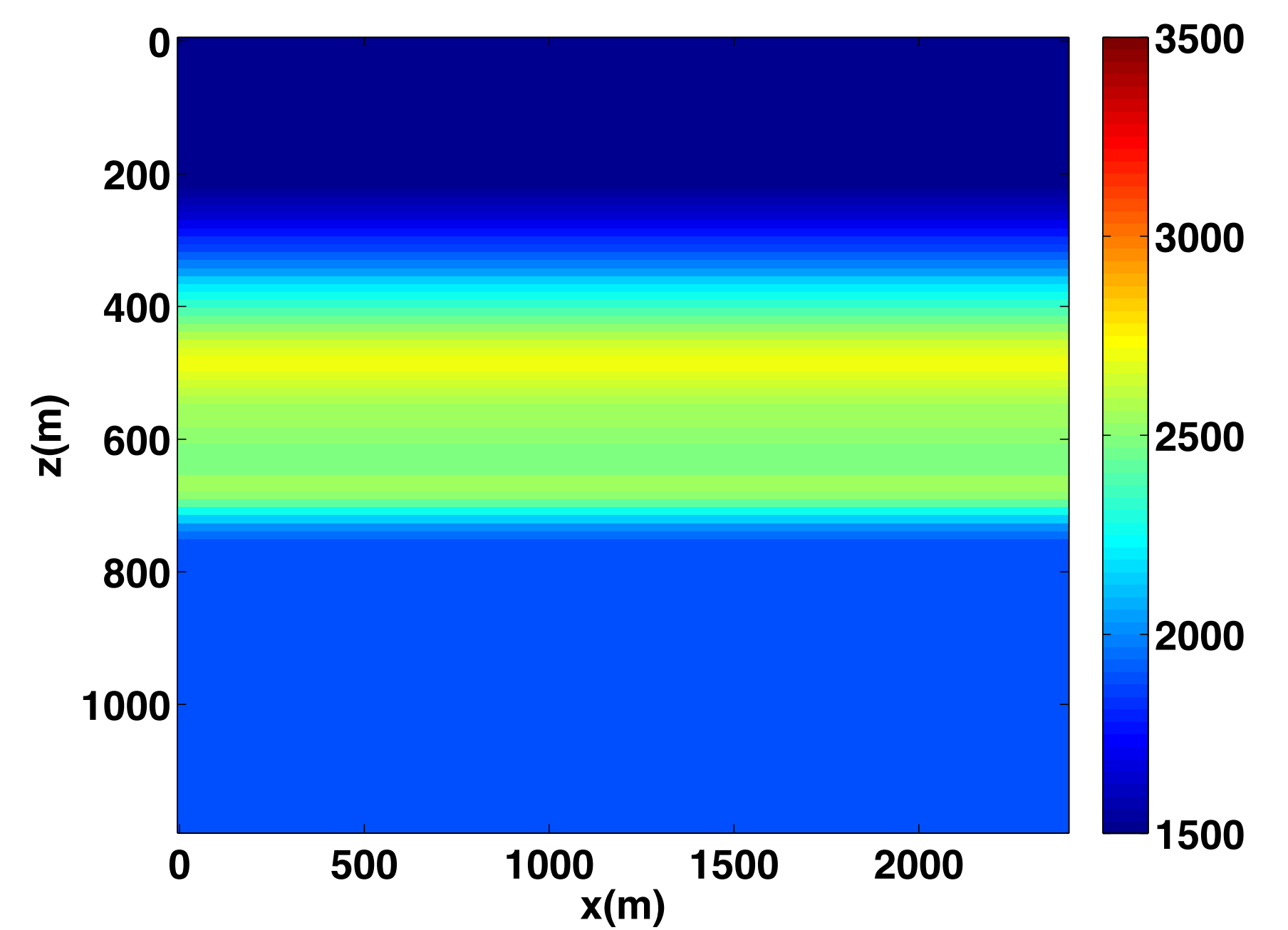
True Model



Initial Model

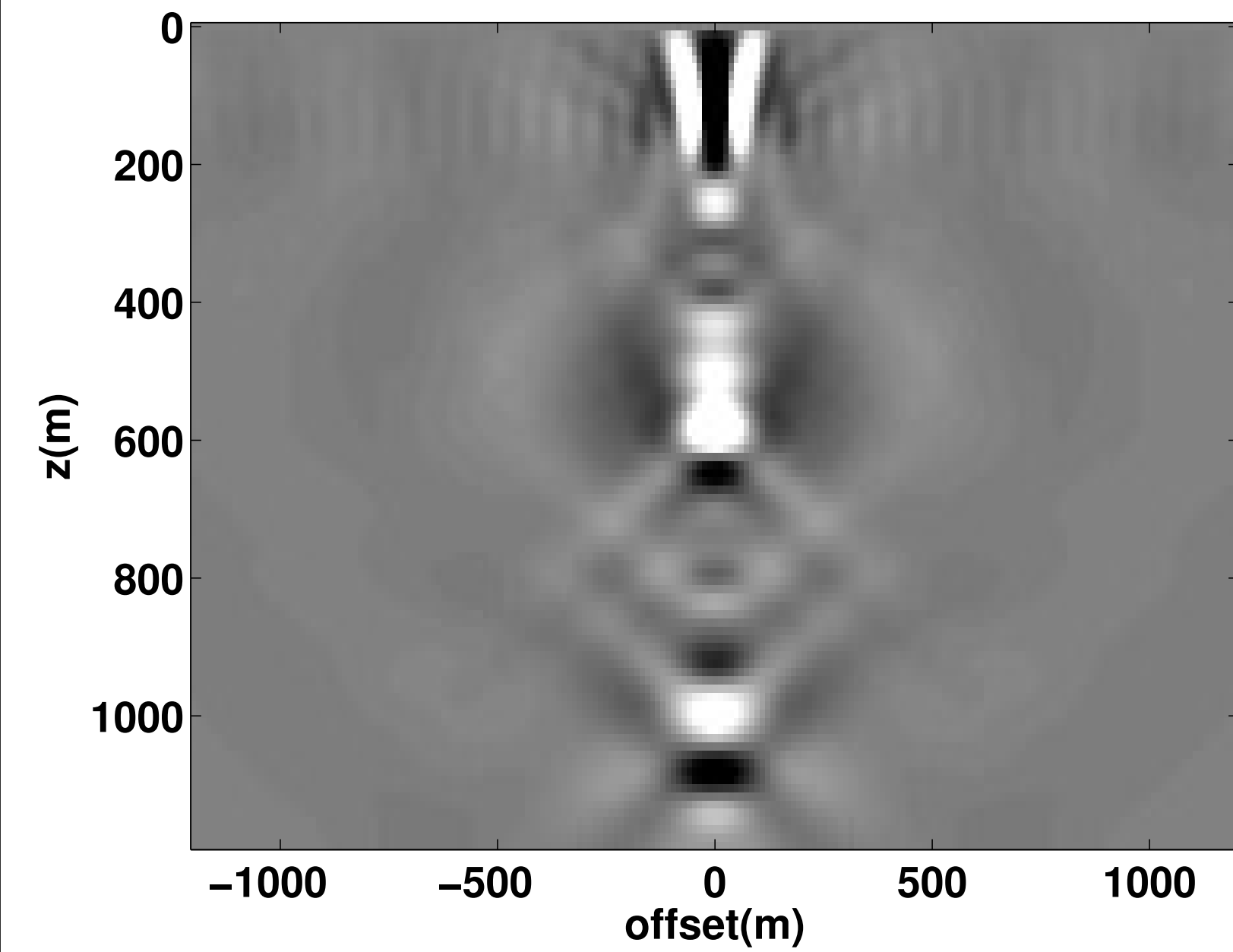


WEMVA

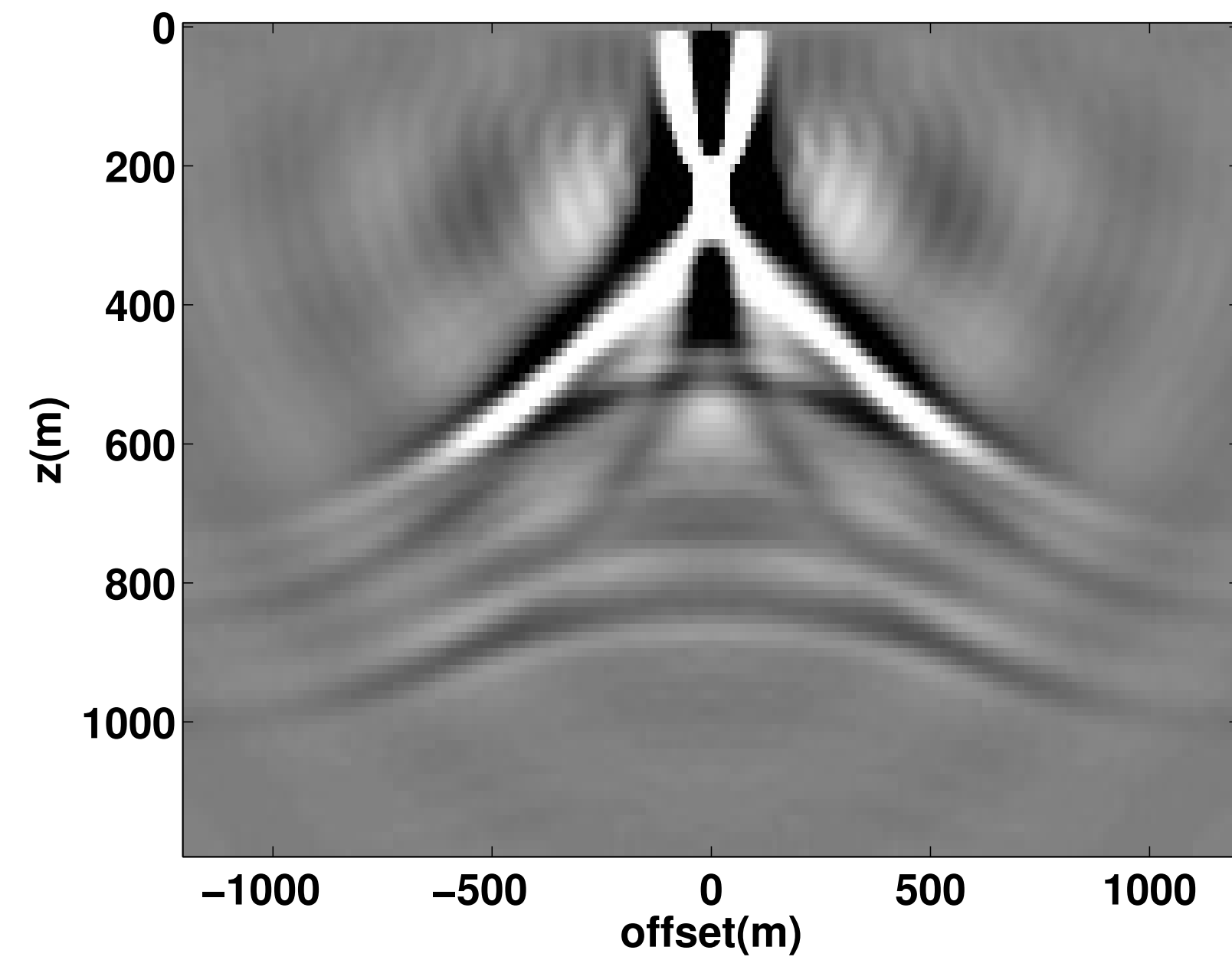


Reflector model

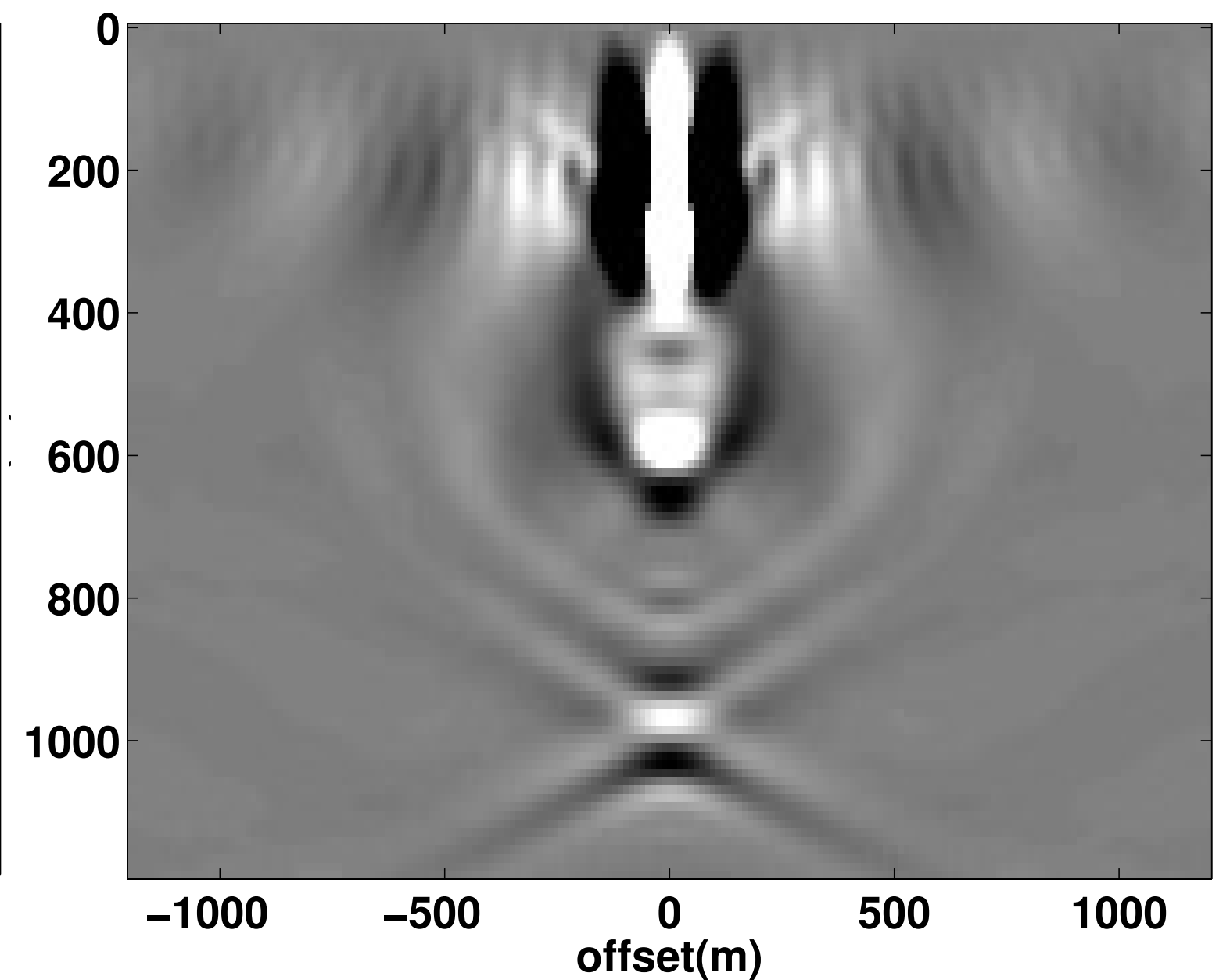
[image gathers]



true model



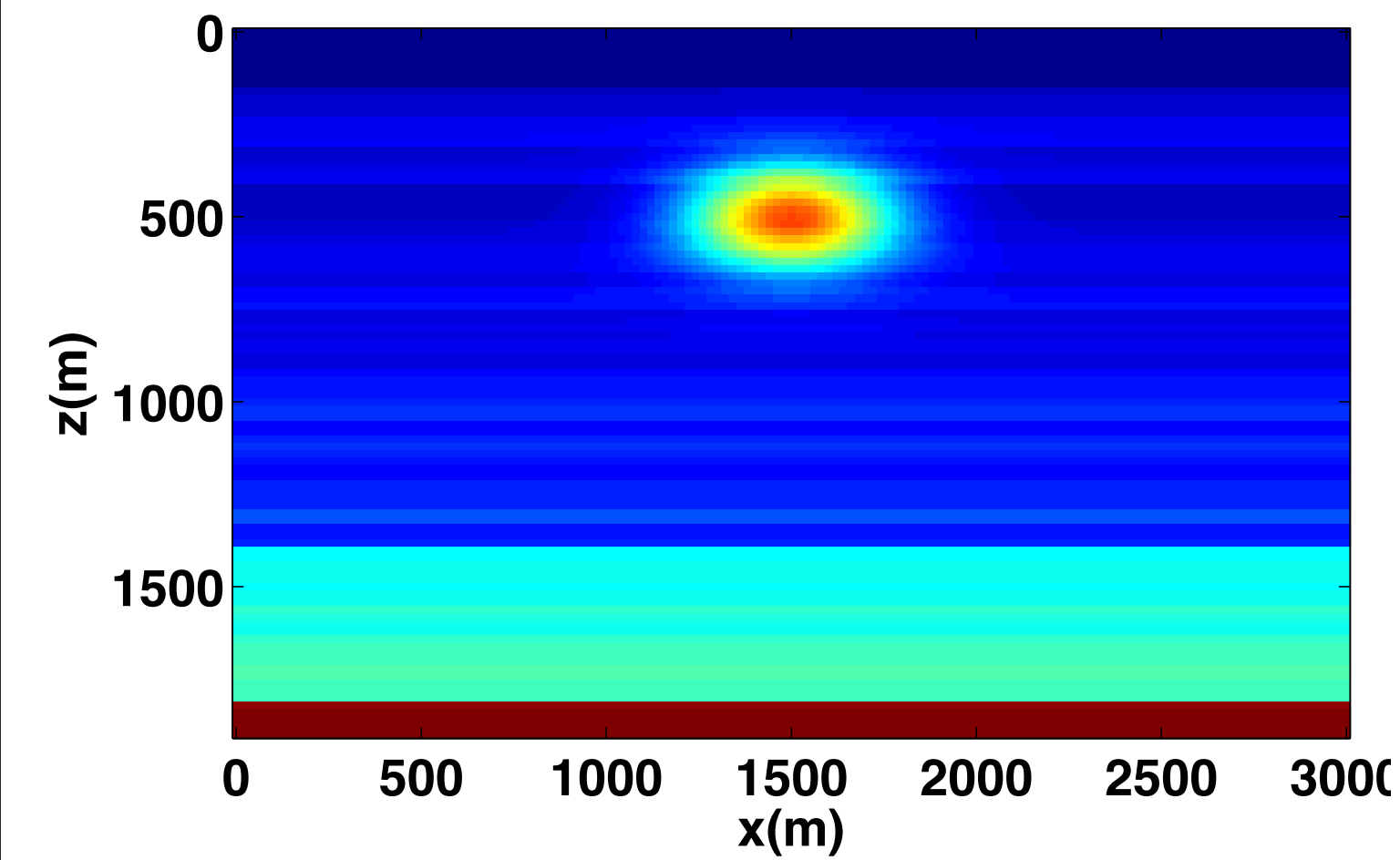
initial model



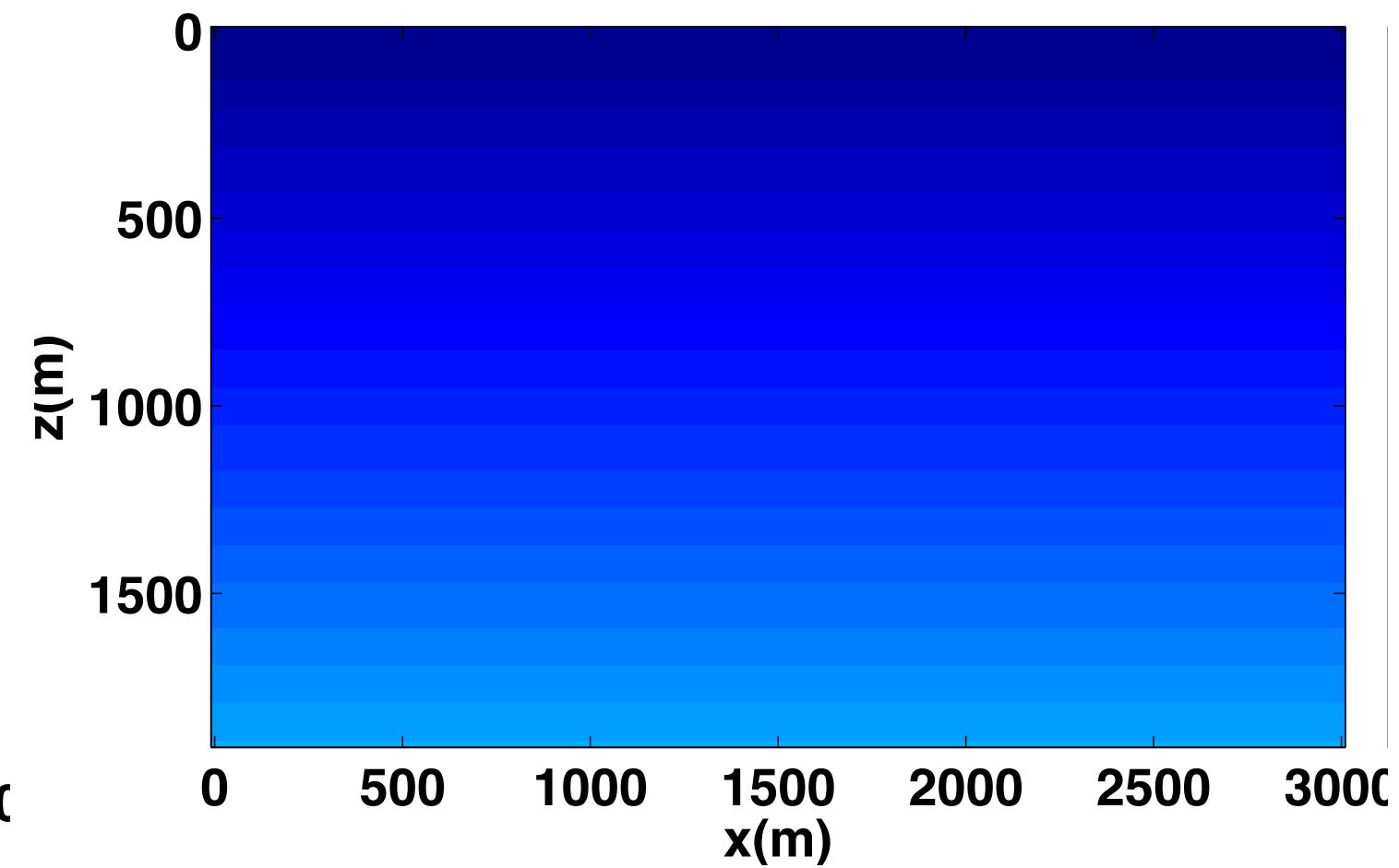
WEMVA

Lens Model

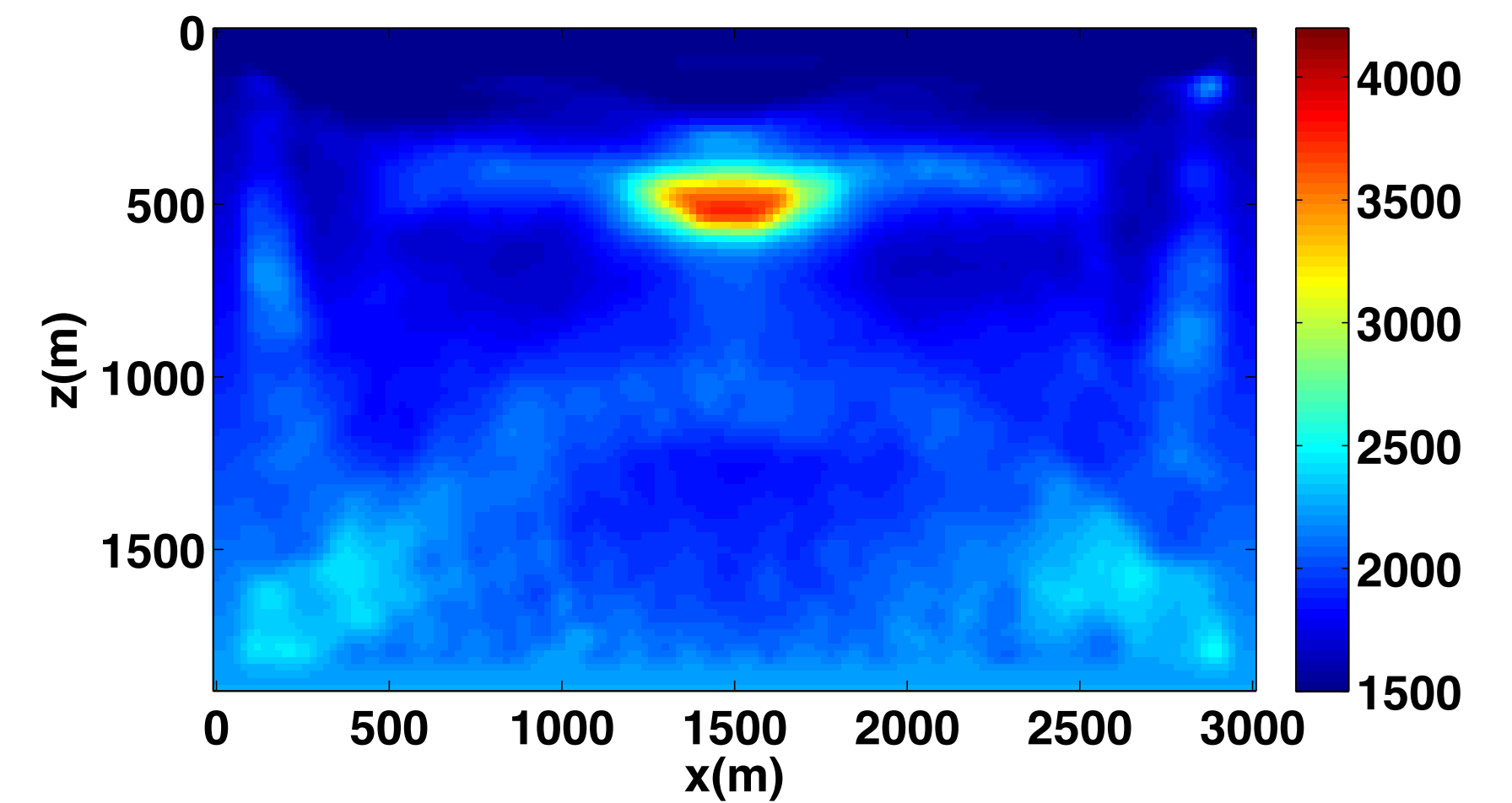
True Model



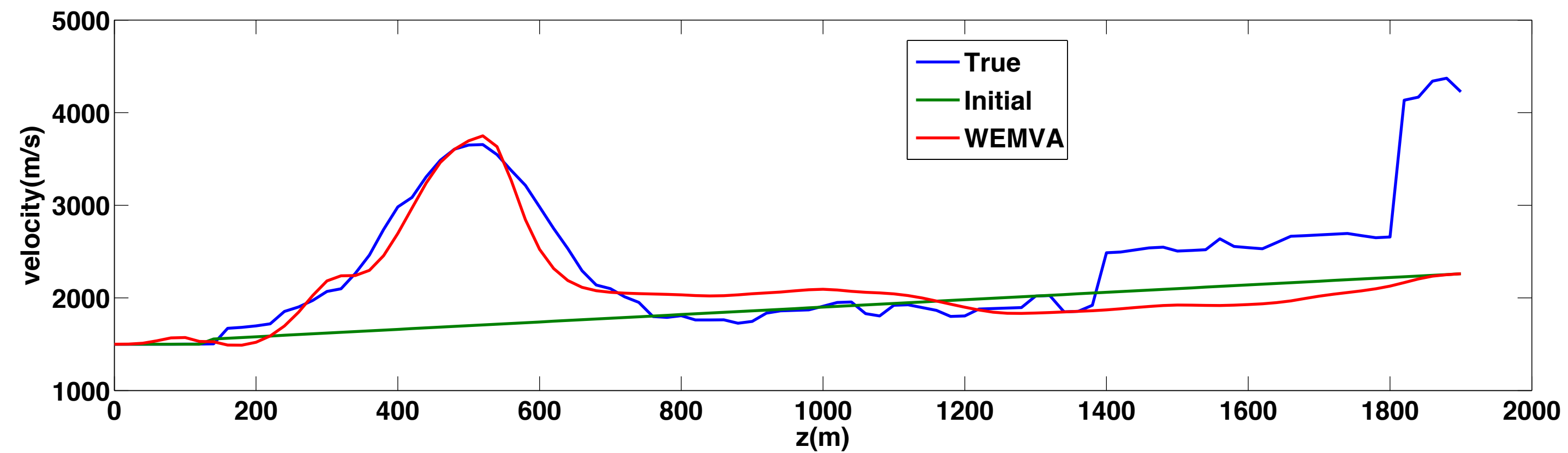
Initial Model



WEMVA

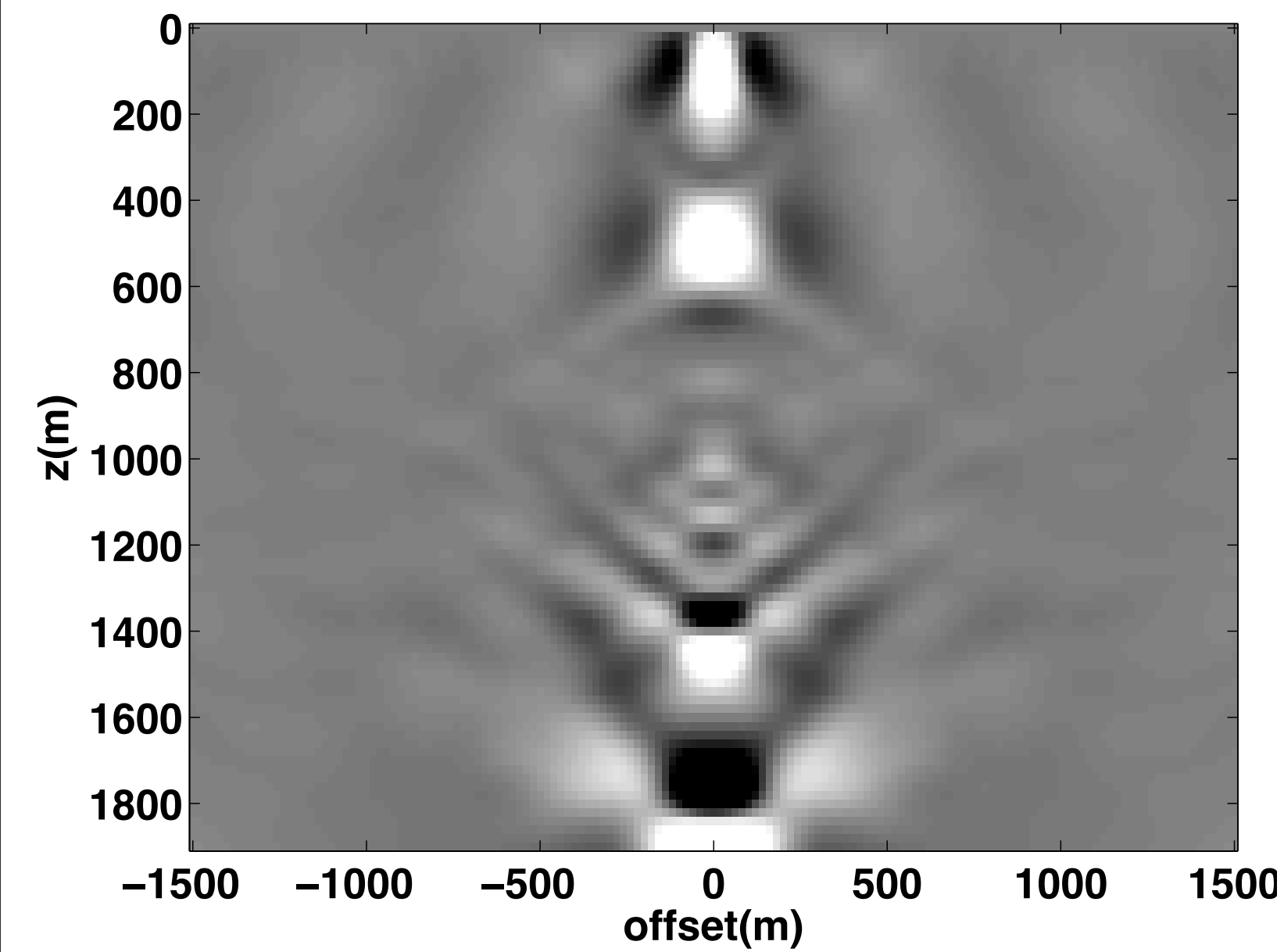


Vertical Trace

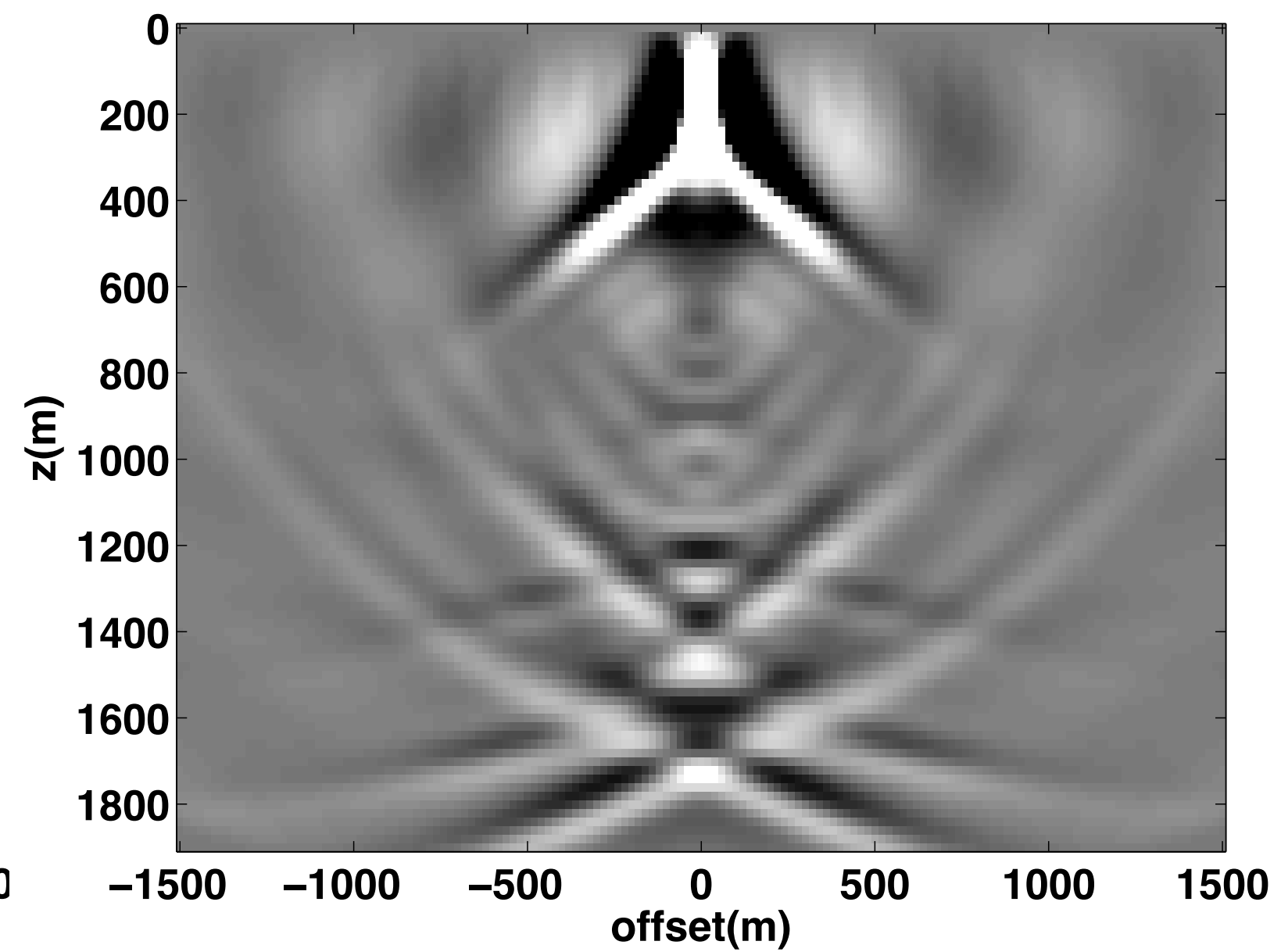


Lens Model

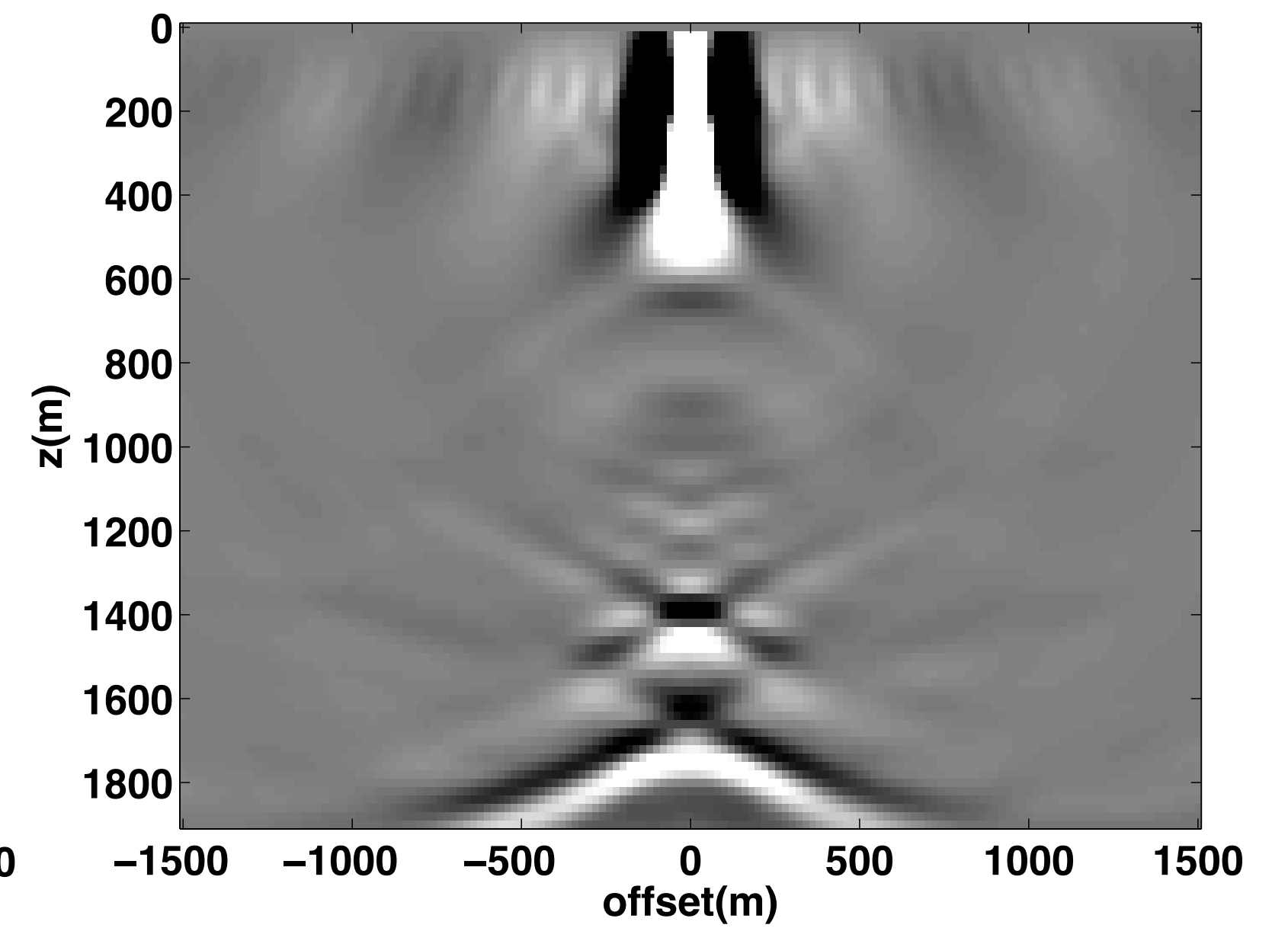
[image gathers]



true model

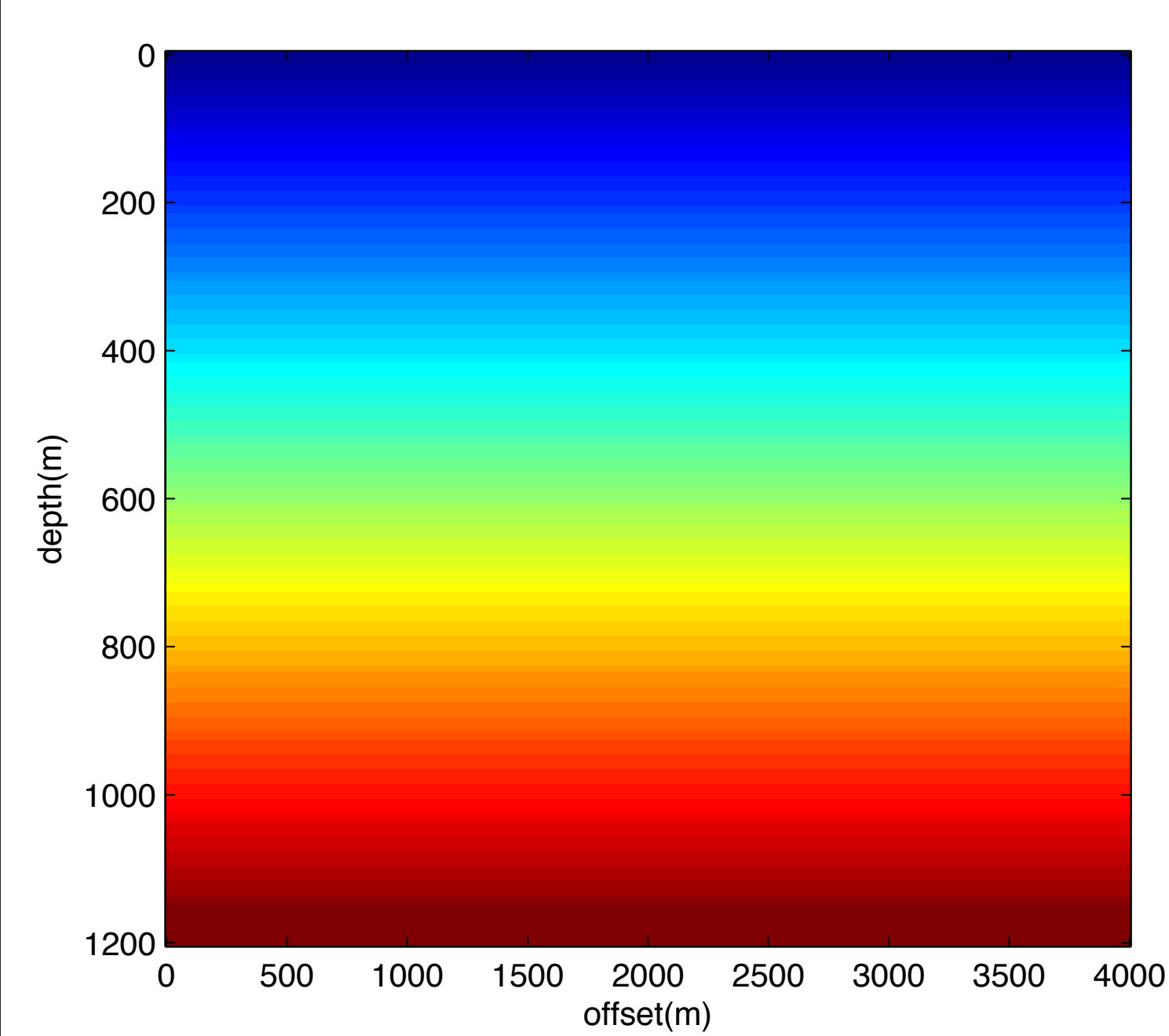


initial model

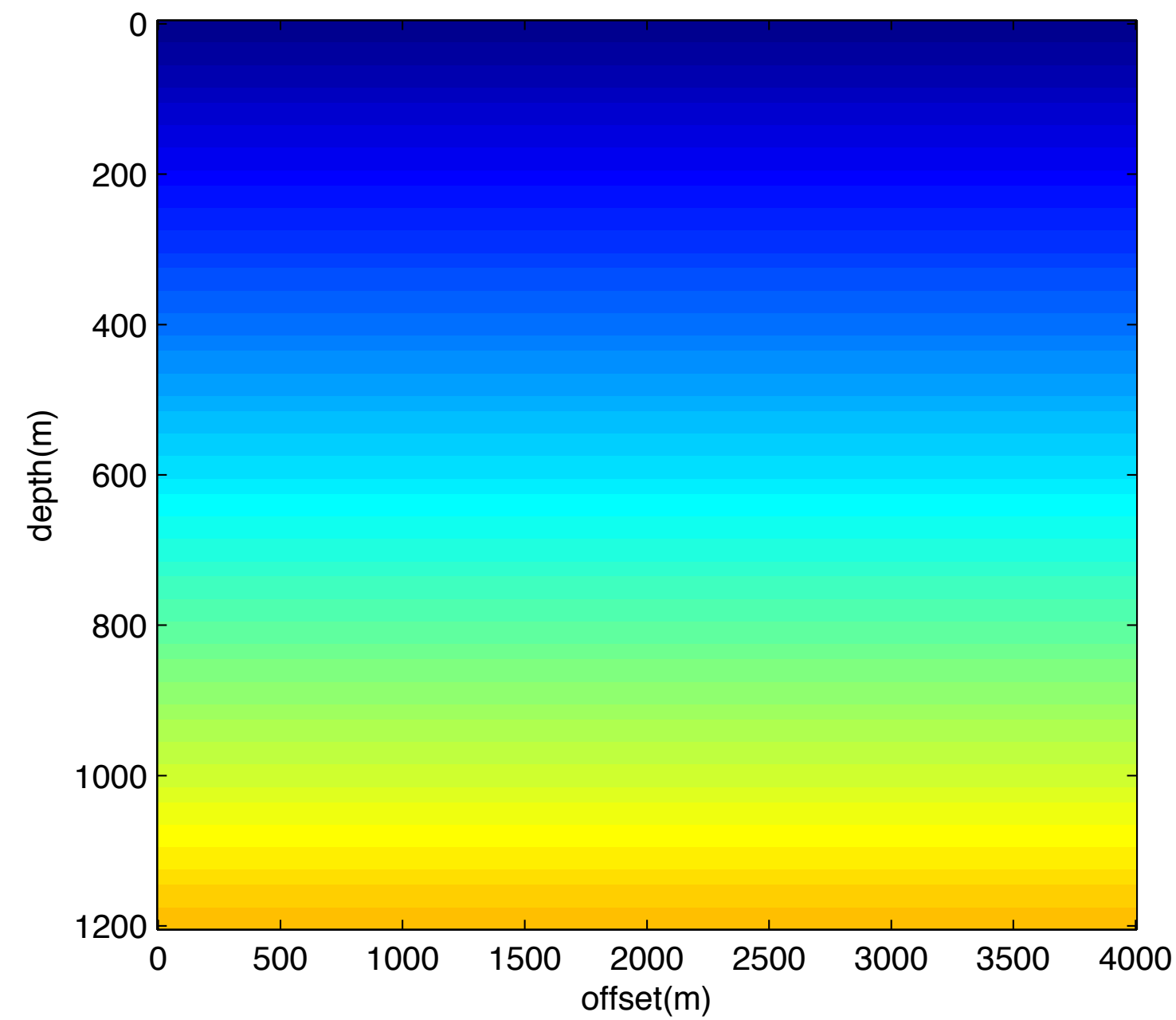


WEMVA

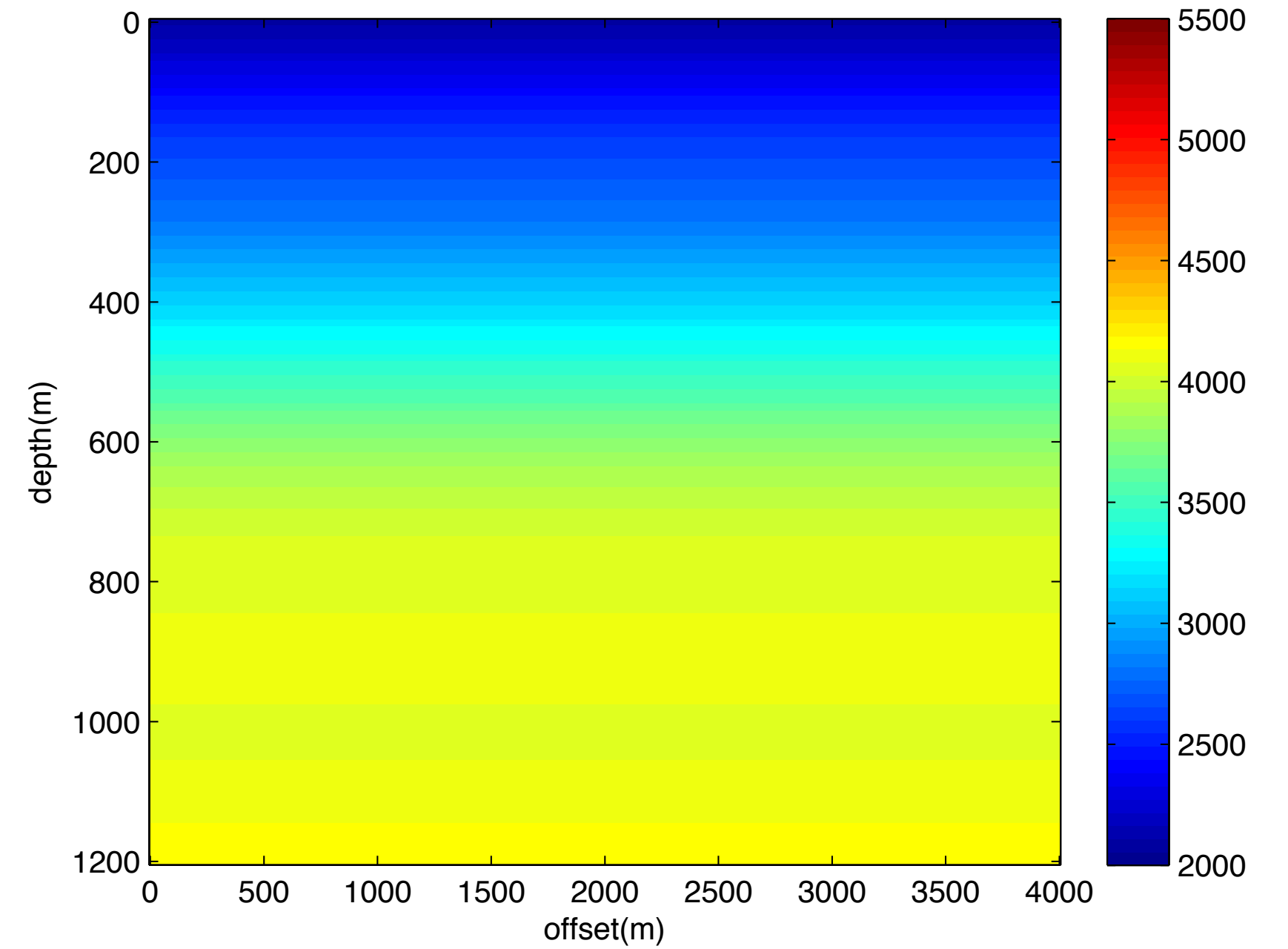
Vertical gradient [diving waves]



true model

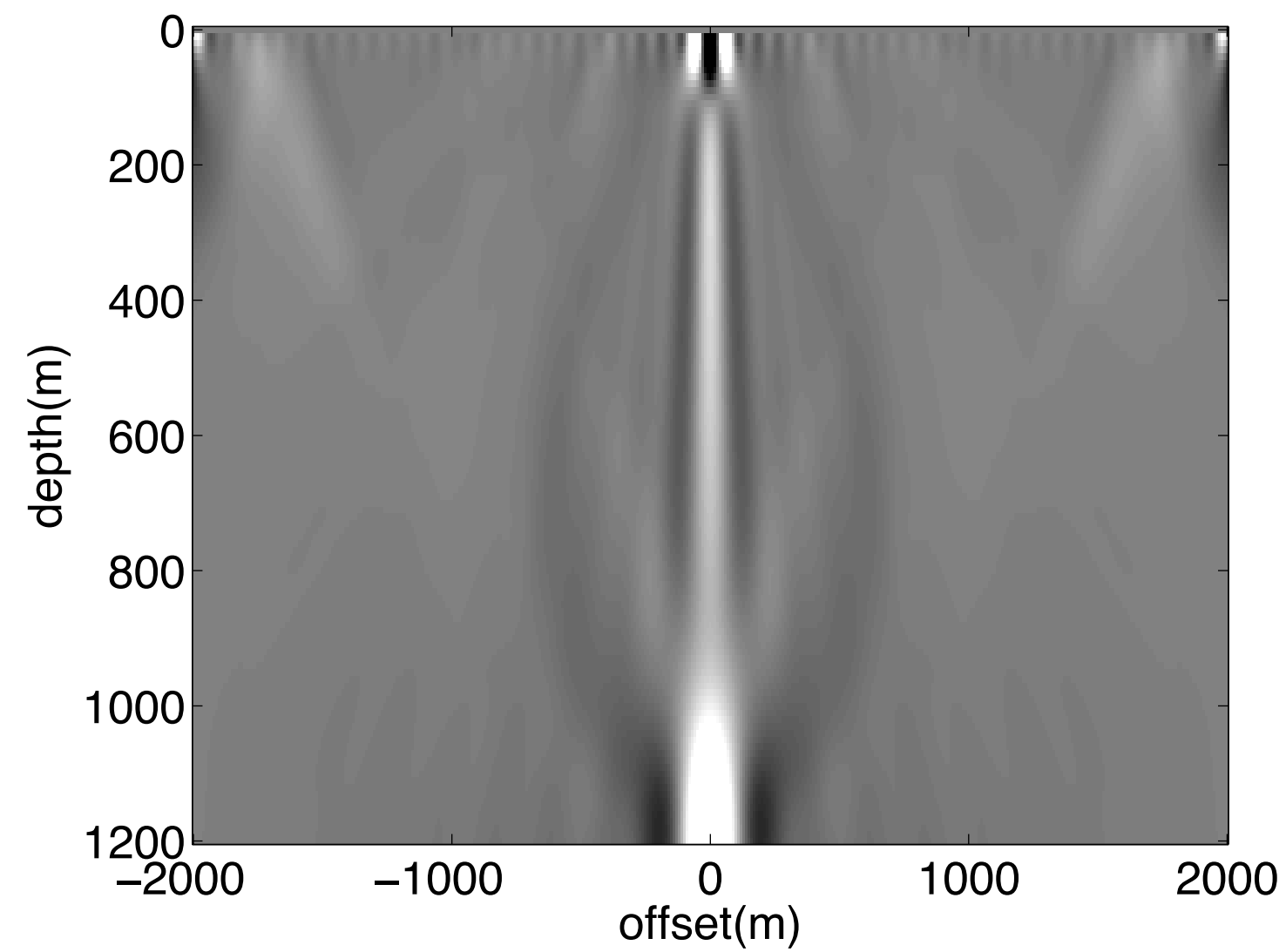


initial model

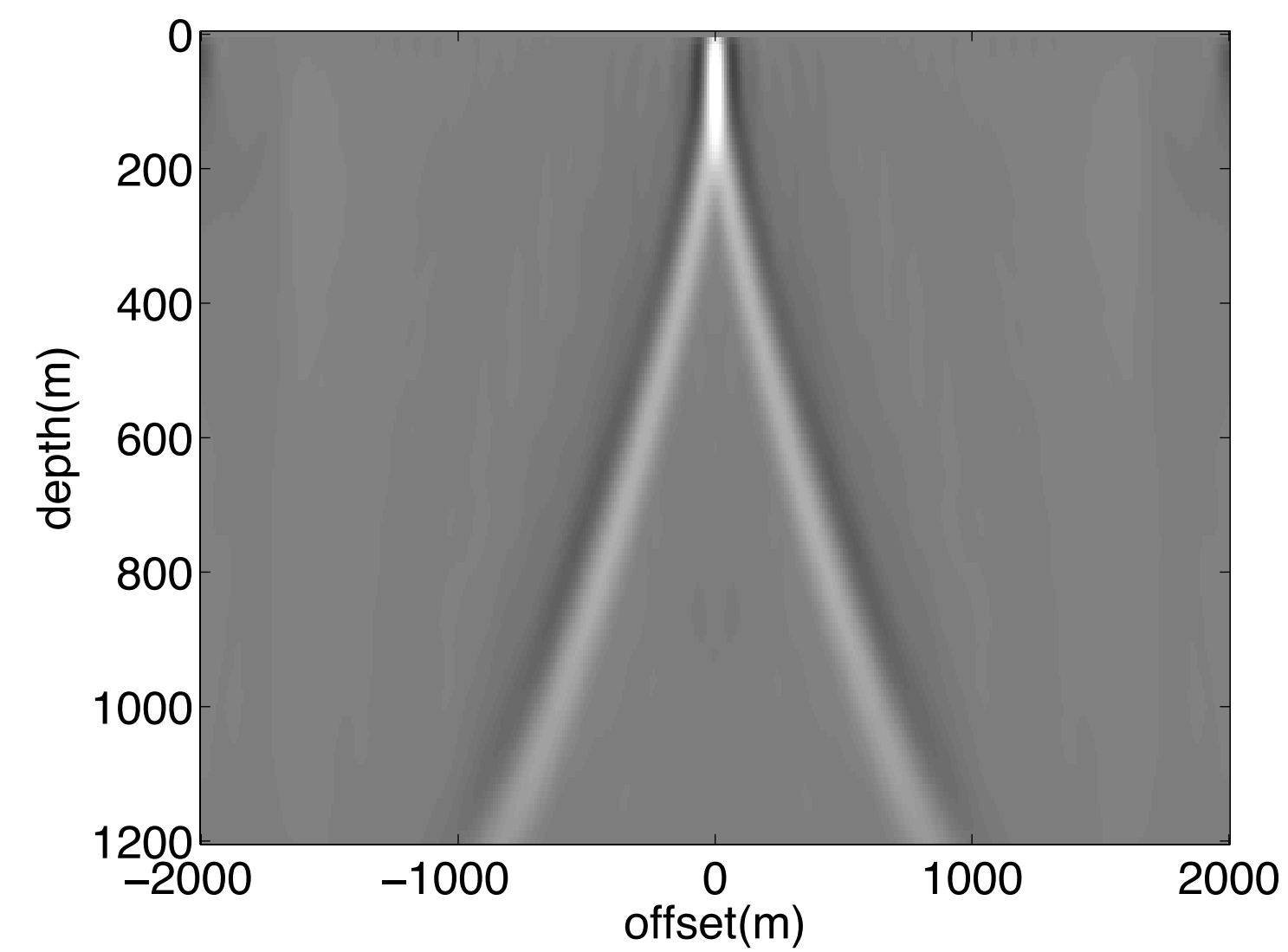


WEMVA

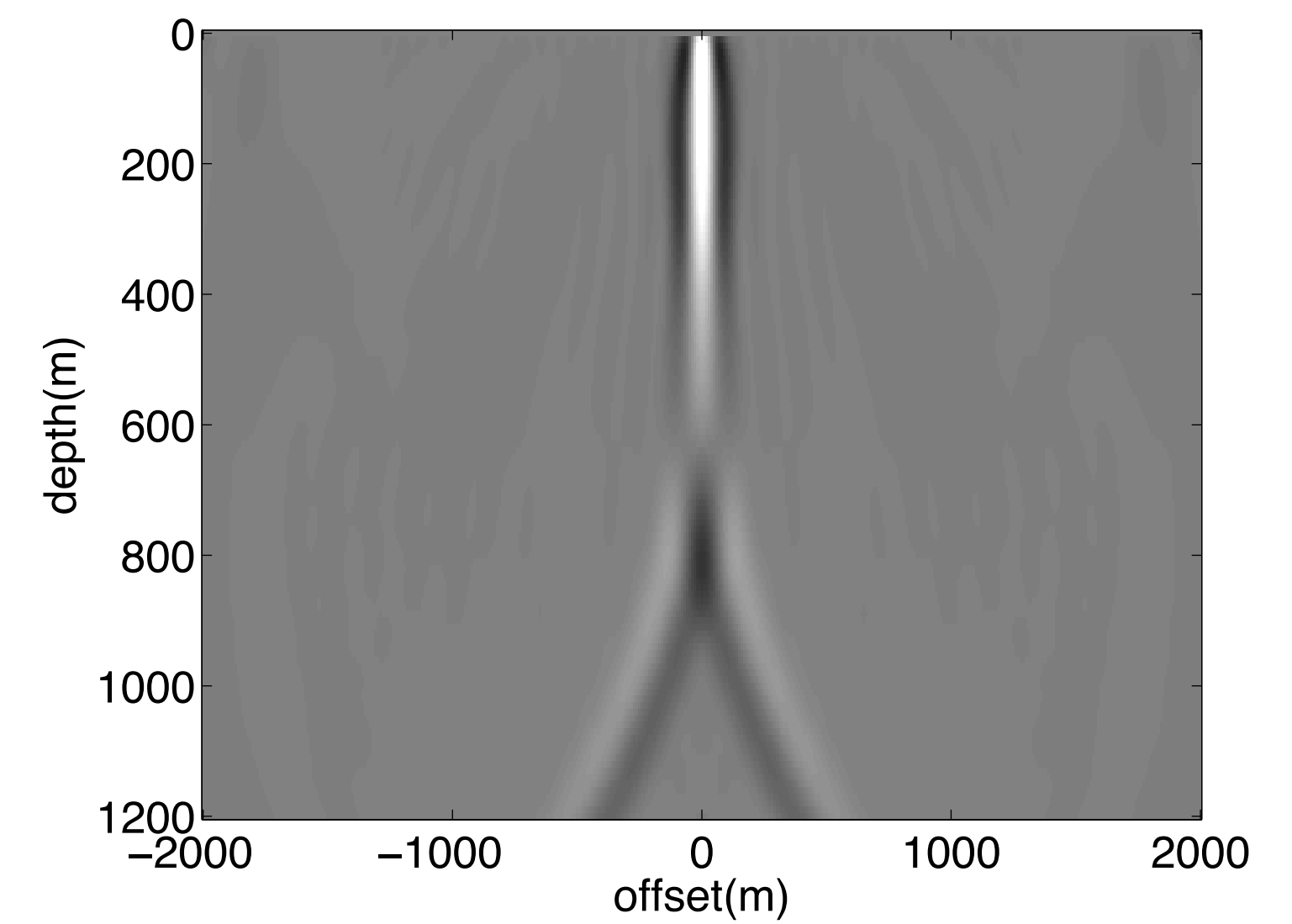
Vertical gradient [image gathers]



true model



initial model



WEMVA

Conclusions

- *probing*s allows us to get *offset* information from *all direction*
- *randomized* trace estimation allows us to *compute* WEMVA objective cheaply

Acknowledgements

Thank you for your attention !

<https://www.slim.eos.ubc.ca/>



SINBAD



This work was in part financially supported by the Natural Sciences and Engineering Research Council of Canada Discovery Grant (22R81254) and the Collaborative Research and Development Grant DNOISE II (375142-08). This research was carried out as part of the SINBAD II project with support from the following organizations: BG Group, BGP, BP, CGG, Chevron, ConocoPhillips, ION, Petrobras, PGS, Statoil, Total SA, WesternGeco, and Woodside.